

S6E1A Series

32-bit Arm[®] Cortex[®]-M0+ FM0+ Microcontroller

The S6E1A Series is a series of highly integrated 32-bit microcontrollers designed for embedded controllers aiming at low power consumption and low cost.

This series has the Arm Cortex-M0+ Processor with on-chip Flash memory and SRAM, and consists of peripheral functions such as various timers, ADCs and communication interfaces (UART, CSIO, I2C, LIN).

The products which are described in this data sheet are placed into TYPE1-M0+ product categories in "FM0+ Family PERIPHERAL MANUAL".

Features

32-bit Arm Cortex-M0+ Core

- ■Processor version: r0p1
- ■Maximum operating frequency: 40 MHz
- Nested Vectored Interrupt Controller (NVIC): 1 NMI (non-maskable interrupt) and 32 peripheral interrupt with 4 selectable interrupt priority levels
- 24-bit System timer (Sys Tick): System timer for OS task management

Bit Band operation

Compatible with Cortex-M3 bit band operation

On-Chip Memories

Flash memory

- □ Up to 88 Kbyte
- □ Read cycle:0 wait-cycle
- □ Security function for code protection

■SRAM

The on-chip SRAM of this series has one independent SRAM.

Multi-function Serial Interface (Max 3channels)

- 128 bytes with FIFO in all channels (The number of FIFO steps varies depending on the settings of the communication mode or bit length.)
- The operation mode of each channel can be selected from one of the following.
 UART
 CSIO
 - □ LIN □ I²C

■UART

- □ Full duplex double buffer
- Parity can be enabled or disabled.
- Built-in dedicated baud rate generator
- External clock available as a serial clock
- Various error detection functions (parity errors, framing errors, and overrun errors)

■CSIO

- □ Full duplex double buffer
- Built-in dedicated baud rate generator
- □ Overrun error detection function
- □ Serial chip select function (ch.1 and ch.3 only)
- Data length: 5 to 16 bits

LIN

- LIN protocol Rev.2.1 supported
- Full duplex double buffer
- □ Master/Slave mode supported
- □ LIN break field generation function (The length is variable between 13 bits and 16 bits.)
- □ LIN break delimiter generation function (The length is variable between 1 bit and 4 bits.)
- □ Various error detection functions available (parity errors, framing errors, and overrun errors)

■I²C

□ Standard-mode (Max: 100 kbps) supported / Fast-mode (Max 400kbps) supported.

Cypress Semiconductor Corporation Document Number: 002-05091 Rev. *D



A/D Converter (Max: 8 channels)

■12-bit A/D Converter

- □ Successive approximation type
- □ Conversion time: 0.8 µs @ 5 V (S6E1A1xC0A) / 2.0 µs (S6E1A1xB0A)
- □ Priority conversion available (2 levels of priority)
- □ Scan conversion mode
- □ Built-in FIFO for conversion data storage (for scan conversion: 16 steps, for priority conversion: 4 steps)

Base Timer (Max: 4 channels)

The operation mode of each channel can be selected from one of the following.

- ■16-bit PWM timer
- ■16-bit PPG timer
- ■16/32-bit reload timer
- ■16/32-bit PWC timer

General-purpose I/O Port

This series can use its pin as a general-purpose I/O port when it is not used for an external bus or a peripheral function. All ports can be set to fast general-purpose I/O ports or slow general-purpose I/O ports. In addition, this series has a port relocate function that can set to which I/O port a peripheral function can be allocated.

- ■All ports are Fast GPIO which can be accessed by 1cycle
- Capable of controlling the pull-up of each pin
- Capable of reading pin level directly
- ■Port relocate function
- ■Up to 37 fast general-purpose I/O ports @48pin package
- ■Certain ports are 5 V tolerant.

See "3. Pin Assignment" and "5. I/O Circuit Type" for details of such pins.

Dual Timer (32/16-bit Down Counter)

The Dual Timer consists of two programmable 32/16-bit down counters. The operation mode of each timer channel can be selected from one of the following.

- Free-running mode
- Periodic mode (= Reload mode)
- ■One-shot mode

Quadrature Position/Revolution Counter (QPRC)

The Quadrature Position/Revolution Counter (QPRC) is used to measure the position of the position encoder. In addition, it can be used as an up/down counter.

- The detection edge for the three external event input pins AIN, BIN and ZIN is configurable.
- 16-bit position counter
- ■16-bit revolution counter
- Two 16-bit compare registers

Multi-function Timer

The Multi-function Timer consists of the following blocks.

- ■16-bit free-run timer × 3 channels
- ■Input capture × 4 channels
- ■Output compare × 6 channels
- ■ADC start compare × 6 channel
- ■Waveform generator × 3 channels
- ■16-bit PPG timer × 3 channels

IGBT mode is contained. The following function can be used to achieve the motor control.

- ■PWM signal output function
- ■DC chopper waveform output function
- Dead time function
- ■Input capture function
- ■ADC start function
- DTIF (motor emergency stop) interrupt function

Real-time Clock (RTC)

The Real-time Clock counts

year/month/day/hour/minute/second/day of the week from year 00 to year 99.

- The RTC can generate an interrupt at a specific time (year/month/day/hour/minute) and can also generate an interrupt in a specific year, in a specific month, on a specific day, at a specific hour or at a specific minute.
- It has a timer interrupt function generating an interrupt upon a specific time or at specific intervals.
- It can keep counting while rewriting the time.
- It can count leap years automatically.



Watch Counter

The Watch Counter wakes up the microcontroller from the low power consumption mode. The clock source can be selected from the main clock, the sub clock, the built-in high-speed CR clock or the built-in low-speed CR clock.

Interval timer: up to 64 s (sub clock: 32.768 kHz)

External Interrupt Controller Unit

■Up to 8 external interrupt input pins

Non-maskable interrupt (NMI) input pin: 1

Watchdog Timer (2 channels)

The watchdog timer generates an interrupt or a reset when the counter reaches a time-out value.

This series consists of two different watchdogs, "hardware" watchdog and "software" watchdog.

The "hardware" watchdog timer is clocked by the built-in low-speed CR oscillator. Therefore, the "hardware" watchdog is active in any low-power consumption modes except RTC mode and STOP mode.

Clock and Reset

Clocks

A clock can be selected from five clock sources (two external oscillators, two built-in CR oscillator, and main PLL).

□ Main clock	: 4 MHz to 40MHz
□ Sub clock	: 32.768 kHz
Built-in high-speed CR clock	: 4 MHz
□ Built-in low-speed CR clock	: 100 kHz
Main PLL clock	

Resets

- □ Reset request from the INITX pin
- Power on reset
- □ Software reset
- □ Watchdog timer reset
- Low-voltage detection reset
- □ Clock supervisor reset

Clock Supervisor (CSV)

The Clock Supervisor monitors the failure of external clocks with a clock generated by a built-in CR oscillator.

- If an external clock failure (clock stop) is detected, a reset is asserted.
- If an external frequency anomaly is detected, an interrupt or a reset is asserted.

Low-voltage Detector (LVD)

This series monitors the voltage on the VCC pin with a 2-stage mechanism. When the voltage falls below a designated voltage, the Low-voltage Detector generates an interrupt or a reset.

- LVD1: error reporting via an interrupt
- LVD2: auto-reset operation

Low Power Consumption Mode

This series has four low power consumption modes.

- ■SLEEP
- ■TIMER
- ■RTC
- ■STOP

Peripheral Clock Gating

The system can reduce the current consumption of the total system with gating the operation clocks of peripheral functions not used.

Debug

- Serial Wire Debug Port (SW-DP)
- Micro Trace Buffer (MTB)

Unique ID

A 41-bit unique value of the device has been set.

Power Supply

Wide voltage range: VCC = 2.7 V to 5.5 V



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Document History
Sales, Solutions, and Legal Information



1. Product Lineup

Memory Size

Product name	S6E1A11B0A S6E1A11C0A	S6E1A12B0A S6E1A12C0A		
On-chip Flash memory	56 Kbyte	88 Kbyte		
On-chip SRAM	6 Kbyte	6 Kbyte		

Function

Product name			S6E1A11B0A S6E1A12B0A	S6E1A11C0A S6E1A12C0A	
Pin count			32 48/52		
CPU			Corte	x-M0+	
CFU	Frequency		40 1	ИНz	
Power supply v	oltage range		2.7 V t	o 5.5 V	
Multi-function S	erial Interface		3 ch.	(Max)	
(UART/CSIO/I ²	C)		ch.0/ch.1/	ch.3: FIFO	
Base Timer (PWC/Reload ti	imer/PWM/PPG)	_	4 ch.	(Max)	
	A/D start compare	6 ch.			
	Input capture	4 ch.			
Multi-function	Free-run timer	3 ch.	1 .	init	
Timer	Output compare	6 ch.	10		
	Waveform	3 ch.			
	generator				
0000	PPG	3 ch.			
QPRC			1 ch.		
Dual Timer			1 unit		
Real-time Clock	κ		1 ເ	ınit	
Watch Counter				ınit	
Watchdog time				⊦ 1 ch. (HW)	
External Interru	pt		8 pins (Max		
I/O port			23 pins (Max)	37 pins (Max)	
12-bit A/D conv			5 ch. (1 unit)	8 ch. (1 unit)	
CSV (Clock Supervisor)			es		
LVD (Low-voltage Detection)		20			
Built-in CR	High-speed			1Hz	
	Low-speed		100 kHz		
Debug Function	1		SW-DP		
Unique ID			Ye	es	

Note:

• All signals of the peripheral function in each product cannot be allocated by limiting the pins of package. It is necessary to use the port relocate function of the I/O port according to your function use. See "14. ELECTRICAL CHARACTERISTICS 14.4 AC Characteristics 14.4.3 Built-in CR Oscillation Characteristics" for

See "14. ELECTRICAL CHARACTERISTICS 14.4 AC Characteristics 14.4.3 Built-in CR Oscillation Characteristics" for accuracy of built-in CR.



2. Packages

Product name Package	S6E1A11B0A S6E1A12B0A	S6E1A11C0A S6E1A12C0A
LQFP: LQB032 (0.80 mm pitch)	0	-
QFN: WNU032 (0.50 mm pitch)	0	-
LQFP: LQA048 (0.50 mm pitch)	-	0
QFN: WNY048 (0.50 mm pitch)	-	0
LQFP: LQC052 (0.65 mm pitch)	-	0

O: Supported

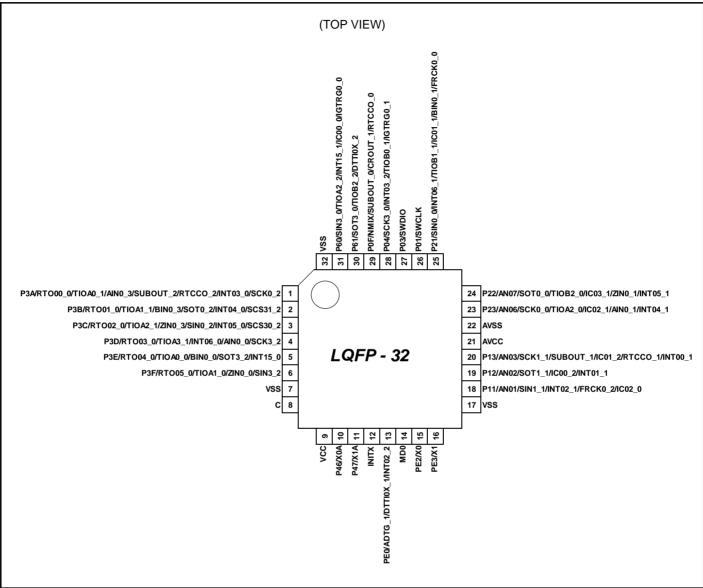
Note:

• See "14. Package Dimensions" for detailed information on each package.



3. Pin Assignment

LQB032

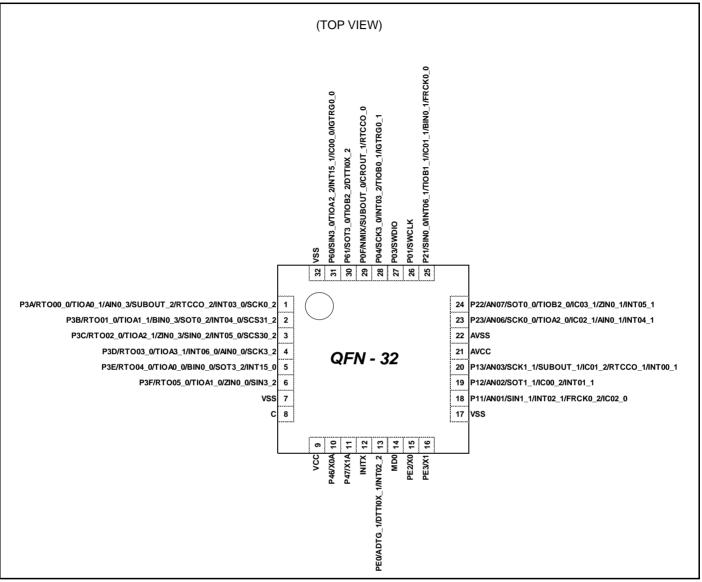


Note:

The number after the underscore ("_") in pin names such as XXX_1 and XXX_2 indicates the relocated port number. For these
pins, there are multiple pins that provide the same function for the same channel.
Use the extended port function register (EPFR) to select the pin.



WNU032

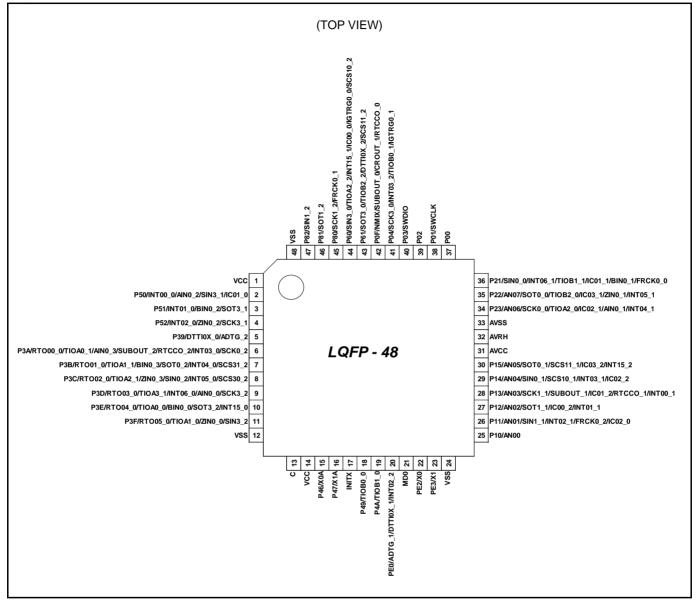


Note:

• The number after the underscore ("_") in pin names such as XXX_1 and XXX_2 indicates the relocated port number. For these pins, there are multiple pins that provide the same function for the same channel. Use the extended port function register (EPFR) to select the pin.



LQA048



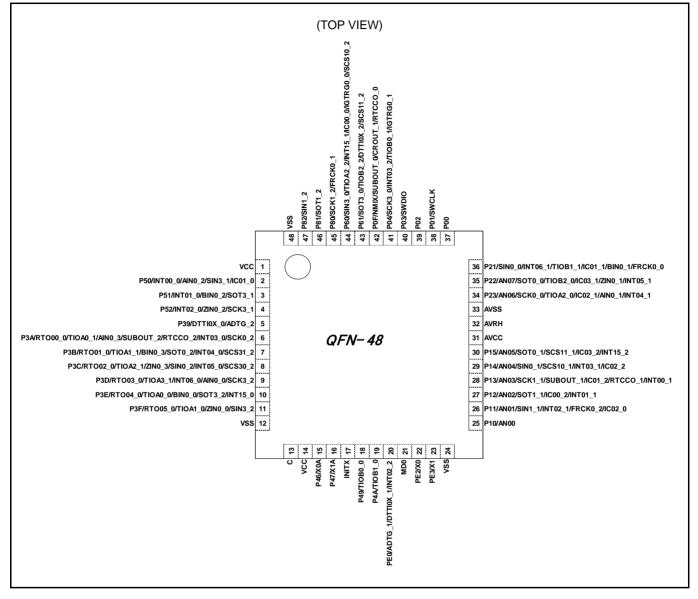
Note:

• The number after the underscore ("_") in pin names such as XXX_1 and XXX_2 indicates the relocated port number. For these pins, there are multiple pins that provide the same function for the same channel. Use the extended port function register (EPFR) to select the pin.





WNY048

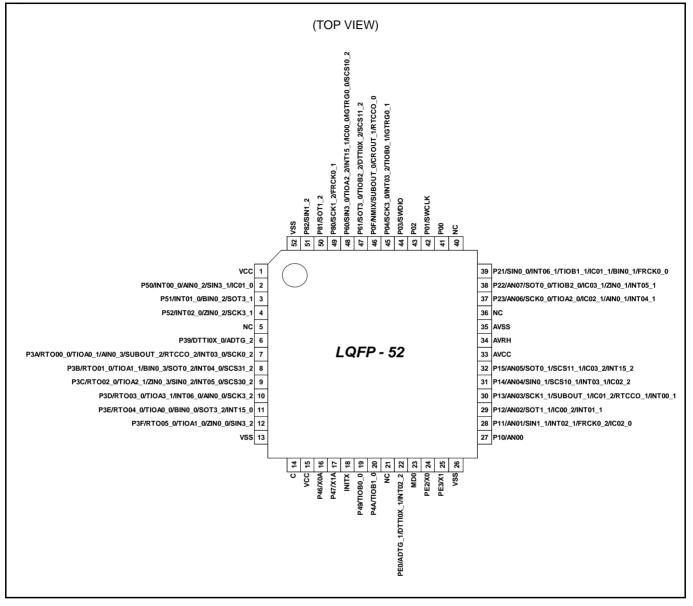


Note:

The number after the underscore ("_") in pin names such as XXX_1 and XXX_2 indicates the relocated port number. For these
pins, there are multiple pins that provide the same function for the same channel.
Use the extended port function register (EPFR) to select the pin.



LQC052



Note:

 The number after the underscore ("_") in a pin name such as XXX_1 and XXX_2 indicates the relocated port number. The channel on such pin has multiple functions, each of which has its own pin name. Use the Extended Port Function Register (EPFR) to select the pin to be used.



4. Pin Descriptions

List of Pin Functions

The number after the underscore ("_") in pin names such as XXX_1 and XXX_2 indicates the relocated port number. For these pins, there are multiple pins that provide the same function for the same channel.

Use the extended port function register (EPFR) to select the pin.

Pin no.					
LQFP-52	LQFP-48 QFN-48	LQFP-32 QFN-32	Pin name	I/O circuit type	Pin state type
1	1	-	VCC	-	
			P50		
			INT00_0		
2	2	-	AIN0_2	l*	J
			SIN3_1		
			IC01_0		
			P51		
2	3		INT01_0	 *	
3	3	-	BIN0_2		J
			SOT3_1		
			P52		J
4	4		INT02_0	 *	
4	4	-	ZIN0_2		
			SCK3_1		
			P39		1
6	5	-	DTTI0X_0	E	
			ADTG_2		
			P3A		J
			RTO00_0		
			TIOA0_1		
7	6	1	AIN0_3	— F	
1	0		SUBOUT_2	F	
			RTCCO_2		
			INT03_0		
			SCK0_2		
			P3B		
			RTO01_0		
			TIOA1_1		
8	7	2	BIN0_3	F	J
			SOT0_2		
			INT04_0		
			SCS31_2		



Pin no.					
LQFP-52	LQFP-48 QFN-48	LQFP-32 QFN-32	Pin name	I/O circuit type	Pin state type
			P3C		
			RTO02_0		
			TIOA2_1		
9	8	3	ZIN0_3	F	J
			SIN0_2		
			INT05_0		
			SCS30_2		
			P3D		
			RTO03_0		
4.0			TIOA3_1		
10	9	4	INT06_0	F	J
			AIN0_0		
			SCK3_2		
			P3E		
	10 5 RTO04_0 TIOA0_0 BIN0_0 SOT3_2 INT15_0				
		5	TIOA0_0		J
11			BIN0_0		
			SOT3_2		
			INT15_0		
			P3F		1
			RTO05_0		
12	11	6	TIOA1_0	F	
			ZIN0_0		
			SIN3_2		
13	12	7	VSS	-	
14	13	8	С	-	
15	14	9	VCC	-	
		10	P46	_	
16	15	10	X0A	D	E
. –	10		P47	_	
17	16	11	X1A	D	F
18	17	12	INITX	В	С
40	10		P49		1.
19	18	-	TIOB0_0	E	
00			P4A		1.
20	19	-	TIOB1_0	——— E	1



Pin no.						
LQFP-52	LQFP-48 QFN-48	LQFP-32 QFN-32	Pin name	I/O circuit type	Pin state type	
			PE0			
22	20	13	ADTG_1	c	J	
	20		DTTI0X_1			
			INT02_2			
23	21	14	MD0	J	D	
24	22	15	PE2	— A	А	
			X0			
25	23	16	PE3	— A	В	
			X1			
26	24	17	VSS	-	1	
27	25	-	P10	G	к	
			AN00			
			P11		L	
			AN01			
28	26	26 18	SIN1_1	— H*		
			INT02_1			
			FRCK0_2			
			IC02_0		L	
			P12			
			AN02			
29	27	19	SOT1_1	H*		
			IC00_2			
	_	_	INT01_1			
			P13			
			AN03			
			SCK1_1			
30	28	20	SUBOUT_1	H*	L	
			IC01_2			
			RTCCO_1			
			INT00_1			
			P14			
			AN04			
31	29	-	SIN0_1	— H*	L	
01	23		SCS10_1			
			INT03_1			
			IC02_2			



Pin no.						
LQFP-52	LQFP-48 QFN-48	LQFP-32 QFN-32	Pin name	I/O circuit type	Pin state type	
			P15			
			AN05			
32	30	-	SOT0_1	H*	L	
52	30	-	SCS11_1	'''		
			IC03_2			
			INT15_2			
33	31	21	AVCC	-		
34	32	-	AVRH	-		
35	33	22	AVSS	-		
			P23			
			AN06			
			SCK0_0			
37	34	23	TIOA2_0	G	L	
			IC02_1			
			AIN0_1			
			INT04_1			
			P22			
			AN07			
				SOT0_0		
38	35	24	TIOB2_0	G	L	
			IC03_1			
			ZIN0_1			
			INT05_1			
			P21		J	
			SIN0_0			
			INT06_1			
39	36	25	TIOB1_1	E		
00	30	20	IC01_1		5	
			BIN0_1			
			FRCK0_0			
41	37	-	P00	E	1	
41	51		P00 P01			
42	38	26		— E	н	
40			SWCLK			
43	39	-	P02	E	1	
44	40	27	P03	— Е	н	
			SWDIO			



	Pin no.						
LQFP-52	LQFP-48 QFN-48	LQFP-32 QFN-32	Pin name	I/O circuit type	Pin state type		
			P04				
			SCK3_0				
45	41	28	INT03_2	I*	J		
			TIOB0_1				
			IGTRG0_1				
			P0F				
			NMIX				
46	42	29	SUBOUT_0	E	G		
			CROUT_1				
			RTCCO_0				
			P61				
		30	SOT3_0		1		
47	43	30	TIOB2_2	I*			
			DTTI0X_2				
		-	SCS11_2				
					P60		
			SIN3_0		J		
			TIOA2_2				
48	44	31	INT15_1	l*			
			IC00_0				
			IGTRG0_0				
		-	SCS10_2				
			P80				
49	45	-	SCK1_2	К	1		
			FRCK0_1				
50	46	-	P81	— к	1		
			SOT1_2				
51	47	-	P82	— к			
51	47	-	SIN1_2		1		
52	48	32	VSS	-			
5,21,36,40	-	-	NC	-			

*:5V tolerant I/O



List of pin functions

The number after the underscore ("_") in a pin name such as XXX_1 and XXX_2 indicates the relocated port number. The channel on such pin has multiple functions, each of which has its own pin name. Use the Extended Port Function Register (EPFR) to select the pin to be used.

Pin				Pin no.	
function	Pin name	Function description	LQFP-52	LQFP-48 QFN-48	LQFP-32 QFN-32
	ADTG_1	A/D converter external trigger	22	20	13
	ADTG_2	input pin	6	5	-
	AN00		27	25	-
	AN01		28	26	18
ADC	AN02		29	27	19
ADC	AN03	A/D converter analog input pin.	30	28	20
	AN04	ANxx describes ADC ch.xx.	31	29	-
	AN05		32	30	-
	AN06		37	34	23
	AN07		38	35	24
	TIOA0_0		11	10	5
Base Timer	TIOA0_1	Base timer ch.0 TIOA pin	7	6	1
0	TIOB0_0		19	18	-
	TIOB0_1	Base timer ch.0 TIOB pin	45	41	28
	TIOA1_0		12	11	6
Base Timer	TIOA1_1	Base timer ch.1 TIOA pin	8	7	2
1	TIOB1_0		20	19	-
	TIOB1_1	Base timer ch.1 TIOB pin	39	36	25
	TIOA2_0		37	34	23
	TIOA2_1	Base timer ch.2 TIOA pin	9	8	3
Base Timer 2	TIOA2_2		48	44	31
2	TIOB2_0		38	35	24
	TIOB2_2	Base timer ch.2 TIOB pin	47	43	30
Base Timer 3	TIOA3_1	Base timer ch.3 TIOA pin	10	9	4
	SWCLK	Serial wire debug interface clock input pin	42	38	26
Debugger	SWDIO	Serial wire debug interface data input / output pin	44	40	27



Pin function	Pin name	Function description	Pin no.		
			LQFP-52	LQFP-48 QFN-48	LQFP-32 QFN-32
	INT00_0	External interrupt request 00 input pin	2	2	-
	INT00_1		30	28	20
	INT01_0	External intervent request 04 input sin	3	3	-
	INT01_1	External interrupt request 01 input pin	29	27	19
	INT02_0		4	4	-
	INT02_1	External interrupt request 02 input pin	28	26	18
	INT02_2		22	20	13
	INT03_0	External interrupt request 03 input pin	7	6	1
	INT03_1		31	29	-
External	INT03_2		45	41	28
Interrupt	INT04_0	External interrupt request 04 input pin	8	7	2
	INT04_1		37	34	23
	INT05_0	External interrupt request 05 input pin	9	8	3
	INT05_1		38	35	24
	INT06_0	External interrupt request 06 input pin	10	9	4
	INT06_1		39	36	25
	INT15_0	External interrupt request 15 input pin	11	10	5
	INT15_1		48	44	31
	INT15_2		32	30	-
	NMIX	Non-Maskable Interrupt input pin	46	42	29



Pin function	Pin name	Function description		Pin no.		
			LQFP-52	LQFP-48 QFN-48	LQFP-32 QFN-32	
	P00		41	37	-	
	P01		42	38	26	
	P02		43	39	-	
	P03	General-purpose I/O port 0	44	40	27	
	P04		45	41	28	
	P0F		46	42	29	
	P10		27	25	-	
	P11		28	26	18	
	P12		29	27	19	
	P13	General-purpose I/O port 1	30	28	20	
0.510	P14	-	31	29	-	
GPIO	P15	-	32	30	-	
	P21		39	36	25	
	P22	General-purpose I/O port 2	38	35	24	
	P23		37	34	23	
	P39		6	5	-	
	P3A	General-purpose I/O port 3	7	6	1	
	P3B		8	7	2	
	P3C		9	8	3	
	P3D		10	9	4	
	P3E		11	10	5	
	P3F		12	11	6	
	P46	General-purpose I/O port 4	16	15	10	
	P47		17	16	11	
	P49		19	18	-	
	P4A		20	19	-	
	P50	General-purpose I/O port 5	2	2	-	
	P51		3	3	-	
GPIO	P52		4	4	-	
	P60	- General-purpose I/O port 6	48	44	31	
	P61		47	43	30	
	P80	General-purpose I/O port 8	49	45	-	
	P81		50	46	-	
	P82		51	47	-	
	PE0*	+	22	20	13	
	PE2	General-purpose I/O port E	24	22	15	
	PE3	1	25	23	16	



Pin function	Pin name	Function description	Pin no.		
			LQFP-52	LQFP-48 QFN-48	LQFP-32 QFN-32
Multi-functio n Serial 0	SIN0_0		39	36	25
	SIN0_1	Multi-function serial interface ch.0 input	31	29	-
	SIN0_2	_ p	9	8	3
	SOT0_0 (SDA0_0)	Multi-function serial interface ch.0 output pin.	38	35	24
	SOT0_1 (SDA0_1)	This pin operates as SOT0 when used as a UART/CSIO/LIN pin (operation mode 0	32	30	-
	SOT0_2 (SDA0_2)	to 3) and as SDA0 when used as an I ² C pin (operation mode 4).	8	7	2
	SCK0_0 (SCL0_0)	Multi-function serial interface ch.0 clock I/O pin. This pin operates as SCK0 when used as a CSIO pin (operation mode 2) and as	37	34	23
	SCK0_2 (SCL0_2)	SCL0 when used as an I ² C pin (operation mode 4).	7	6	1
	SIN1_1	Multi-function serial interface ch.1 input	28	26	18
	SIN1_2	pin	51	47	-
	SOT1_1 (SDA1_1)	Multi-function serial interface ch.1 output pin.	29	27	19
	SOT1_2 (SDA1_2)	This pin operates as SOT1 when used as a UART/CSIO/LIN pin (operation mode 0 to 3) and as SDA1 when used as an I ² C pin (operation mode 4).	50	46	-
Multi-functio	SCK1_1 (SCL1_1)	Multi-function serial interface ch.1 clock I/O pin.	30	28	20
n Serial 1	SCK1_2 (SCL1_2)	This pin operates as SCK1 when used as a CSIO pin (operation mode 2) and as SCL1 when used as an I ² C pin (operation mode 4).	49	45	-
	SCS10_1	Multi-function serial interface ch.1 serial chip select 0 output/input pin.	31	29	-
	SCS10_2		48	44	-
	SCS11_1	Multi-function serial interface ch.1 serial chip select 1 output pin.	32	30	-
	SCS11_2		47	43	-
	SIN3_0	Multi-function serial interface ch.3 input pin	48	44	31
	SIN3_1		2	2	-
	SIN3_2		12	11	6
	SOT3_0 (SDA3_0)	Multi-function serial interface ch.3 output pin.	47	43	30
	SOT3_1 (SDA3_1)	This pin operates as SOT3 when used as a UART/CSIO/LIN pin (operation mode 0	3	3	-
Multi- function Serial 3	SOT3_2 (SDA3_2)	to 3) and as SDA3 when used as an I ² C pin (operation mode 4).	11	10	5
	SCK3_0 (SCL3_0)	Multi-function serial interface ch.3 clock I/O pin.	45	41	28
	SCK3_1 (SCL3_1)	This pin operates as SCK3 when used as a CSIO (operation mode 2) and as SCL3	4	4	-
	SCK3_2 (SCL3_2)	when used as an I ² C pin (operation mode 4).	10	9	4
	SCS30_2	Multi-function serial interface ch.3 serial chip select 0 input/output pin.	9	8	3
	SCS31_2	Multi-function serial interface ch.3 serial chip select 1 output pin.	8	7	2



Pin function	Pin name	Function description	Pin no.		
			LQFP-52	LQFP-48 QFN-48	LQFP-32 QFN-32
	DTTI0X_0	Input signal of waveform generator	6	5	-
	DTTI0X_1	controlling RTO00 to RTO05 outputs of Multi-function Timer 0.	22	20	13
	DTTI0X_2		47	43	30
	FRCK0_0	16-bit free-run timer ch.0 external clock input pin.	39	36	25
	FRCK0_1		49	45	-
	FRCK0_2		28	26	18
	IC00_0		48	44	31
	IC00_2		29	27	19
	IC01_0		2	2	-
	IC01_1		39	36	25
	IC01_2	16-bit input capture input pin of	30	28	20
	IC02_0	 Multi-function timer 0. ICxx describes channel number. 	28	26	18
	IC02_1		37	34	23
	IC02_2		31	29	-
	IC03_1	-	38	35	24
	IC03_2		32	30	-
Multi-functio n Timer 0	RTO00_0 (PPG00_0)	Waveform generator output pin of Multi-function timer 0. This pin operates as PPG00 when it is used in PPG0 output mode.	7	6	1
	RTO01_0 (PPG00_0)	Waveform generator output pin of Multi-function timer 0. This pin operates as PPG00 when it is used in PPG0 output mode.	8	7	2
	RTO02_0 (PPG02_0)	Waveform generator output pin of Multi-function timer 0. This pin operates as PPG02 when it is used in PPG0 output mode.	9	8	3
	RTO03_0 (PPG02_0)	Waveform generator output pin of Multi-function timer 0. This pin operates as PPG02 when it is used in PPG0 output mode.	10	9	4
	RTO04_0 (PPG04_0)	Waveform generator output pin of Multi-function timer 0. This pin operates as PPG04 when it is used in PPG0 output mode.	11	10	5
	RTO05_0 (PPG04_0)	Waveform generator output pin of Multi-function timer 0. This pin operates as PPG04 when it is used in PPG0 output mode.	12	11	6
	IGTRG0_0		48	44	31
	IGTRG0_1	PPG IGBT mode external trigger input pin	45	41	28

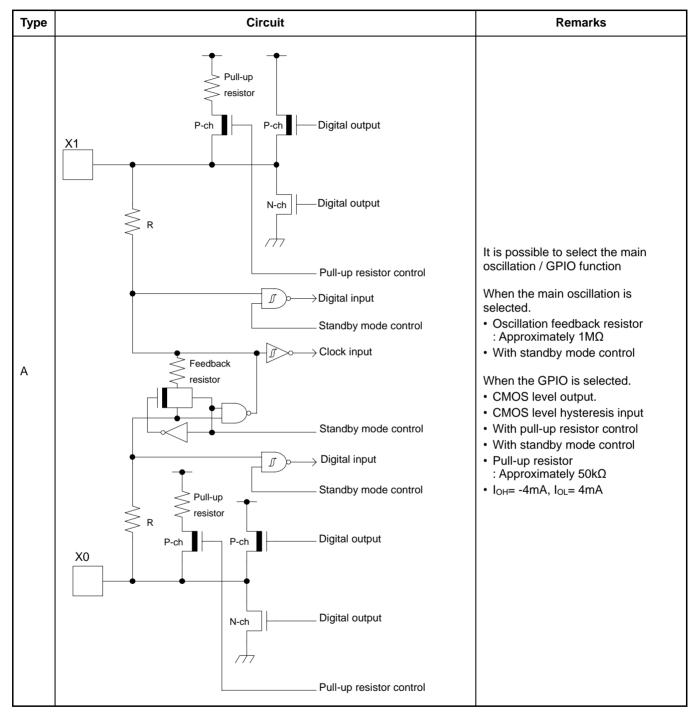


Pin function	Pin name	Function description	Pin no.		
			LQFP-52	LQFP-48 QFN-48	LQFP-32 QFN-32
	AIN0_0	QPRC ch.0 AIN input pin	10	9	4
	AIN0_1		37	34	23
	AIN0_2		2	2	-
	AIN0_3		7	6	1
Ourselasture	BIN0_0		11	10	5
Quadrature Position/ Revolution	BIN0_1		39	36	25
	BIN0_2	QPRC ch.0 BIN input pin	3	3	-
Counter	BIN0_3		8	7	2
	ZIN0_0		12	11	6
	ZIN0_1		38	35	24
	ZIN0_2	QPRC ch.0 ZIN input pin	4	4	-
	ZIN0_3		9	8	3
	RTCCO_0	0.5-seconds pulse output pin of Real-time	46	42	29
	RTCCO_1		30	28	20
Real-time	RTCCO_2		7	6	1
clock	SUBOUT_0	Sub clock output pin	46	42	29
	SUBOUT_1		30	28	20
	SUBOUT_2		7	6	1
RESET	INITX	External Reset Input pin. A reset is valid when INITX="L".	18	17	12
Mode	MD0	Mode 0 pin. During normal operation, input MD0="L". During serial programming to Flash memory, input MD0="H".	23	21	14
	VCC	Power supply pin	1	1	-
POWER	VCC	Power supply pin	15	14	9
	VSS	GND pin	13	12	7
GND	VSS	GND pin	26	24	17
	VSS	GND pin	52	48	32
	X0	Main clock (oscillation) input pin	24	22	15
	X0A	Sub clock (oscillation) input pin	16	15	10
CLOCK	X1	Main clock (oscillation) I/O pin	25	23	16
OLOOK	X1A	Sub clock (oscillation) I/O pin	17	16	11
	CROUT_1	Built-in high-speed CR oscillation clock output port	46	42	29
Analog	AVCC	A/D converter analog power supply pin	33	31	21
POWĔR	AVRH	A/D converter analog reference voltage input pin	34	32	-
Analog GND	AVSS	A/D converter analog reference voltage input pin	35	33	22
C pin	С	Power supply stabilization capacitance pin	14	13	8

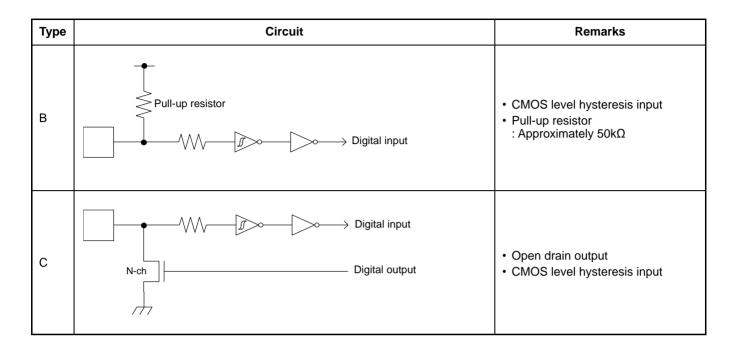
*: PE0 is an open drain pin, cannot output high.



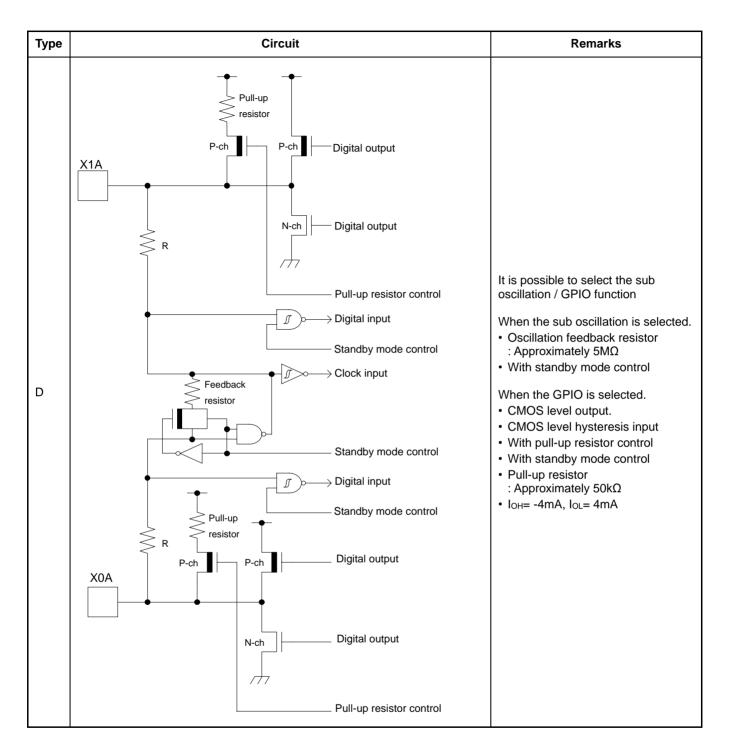
5. I/O Circuit Type



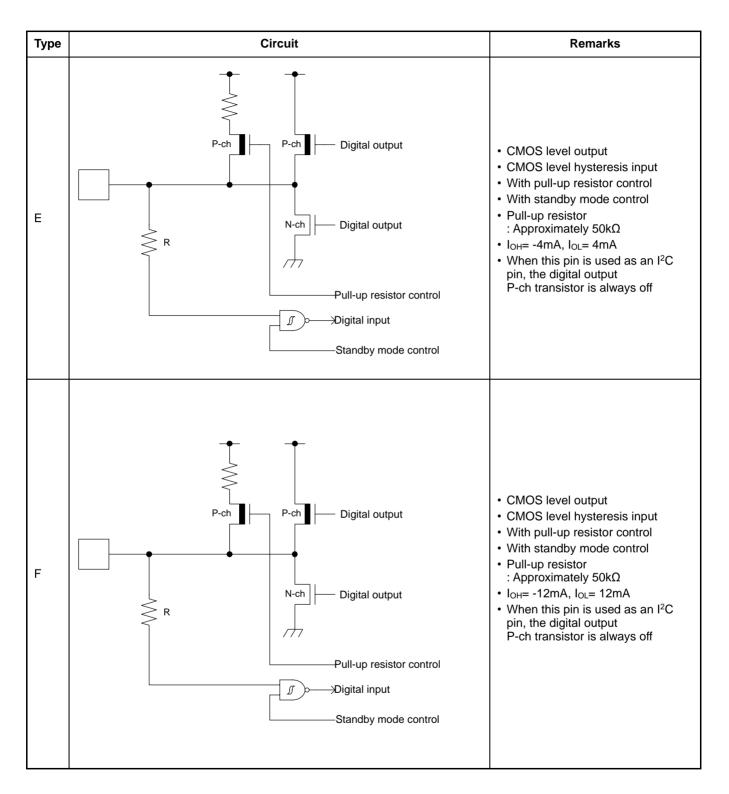




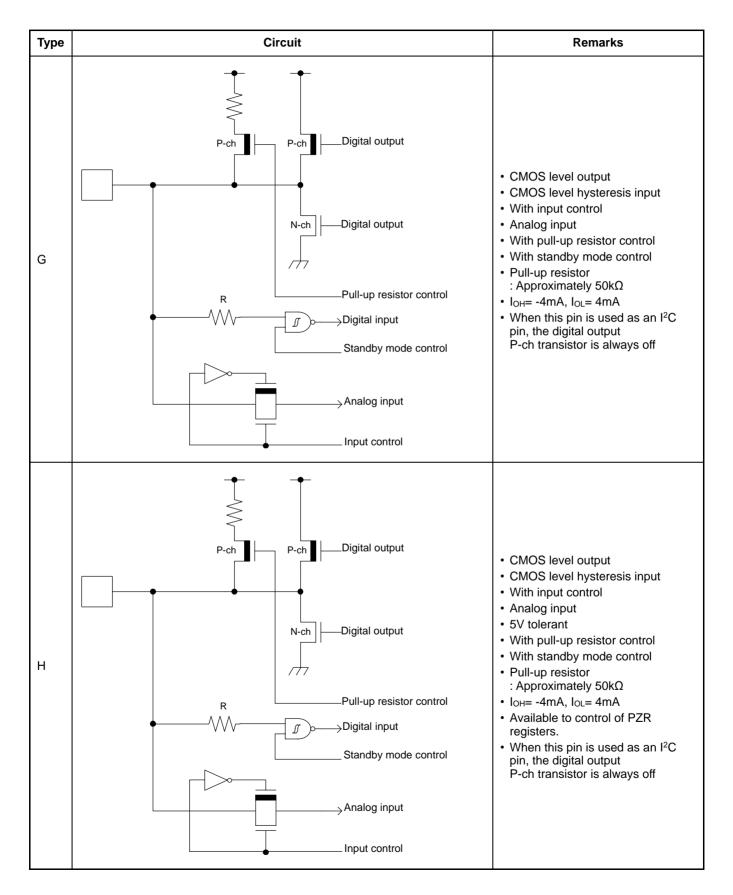




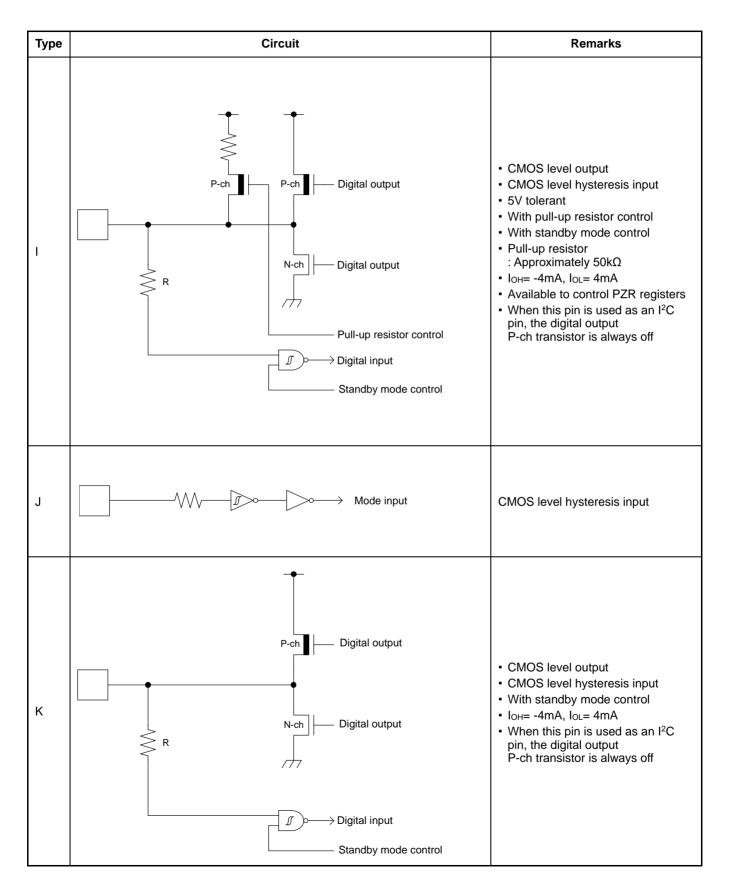














6. Handling Precautions

Any semiconductor devices have inherently a certain rate of failure. The possibility of failure is greatly affected by the conditions in which they are used (circuit conditions, environmental conditions, etc.). This page describes precautions that must be observed to minimize the chance of failure and to obtain higher reliability from your Cypress semiconductor devices.

6.1 Precautions for Product Design

This section describes precautions when designing electronic equipment using semiconductor devices.

Absolute Maximum Ratings

Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of certain established limits, called absolute maximum ratings. Do not exceed these ratings.

Recommended Operating Conditions

Recommended operating conditions are normal operating ranges for the semiconductor device. All the device's electrical characteristics are warranted when operated within these ranges.

Always use semiconductor devices within the recommended operating conditions. Operation outside these ranges may adversely affect reliability and could result in device failure.

No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their sales representative beforehand.

Processing and Protection of Pins

These precautions must be followed when handling the pins which connect semiconductor devices to power supply and input/output functions.

1. Preventing Over-Voltage and Over-Current Conditions

Exposure to voltage or current levels in excess of maximum ratings at any pin is likely to cause deterioration within the device, and in extreme cases leads to permanent damage of the device. Try to prevent such overvoltage or over-current conditions at the design stage.

2. Protection of Output Pins

Shorting of output pins to supply pins or other output pins, or connection to large capacitance can cause large current flows. Such conditions if present for extended periods of time can damage the device. Therefore, avoid this type of connection.

3. Handling of Unused Input Pins

Unconnected input pins with very high impedance levels can adversely affect stability of operation. Such pins should be connected through an appropriate resistance to a power supply pin or ground pin.

Code: DS00-00004-2Ea



Latch-up

Semiconductor devices are constructed by the formation of P-type and N-type areas on a substrate. When subjected to abnormally high voltages, internal parasitic PNPN junctions (called thyristor structures) may be formed, causing large current levels in excess of several hundred mA to flow continuously at the power supply pin. This condition is called latch-up.

CAUTION: The occurrence of latch-up not only causes loss of reliability in the semiconductor device, but can cause injury or damage from high heat, smoke or flame. To prevent this from happening, do the following:

- 1. Be sure that voltages applied to pins do not exceed the absolute maximum ratings. This should include attention to abnormal noise, surge levels, etc.
- 2. Be sure that abnormal current flows do not occur during the power-on sequence.

Observance of Safety Regulations and Standards

Most countries in the world have established standards and regulations regarding safety, protection from electromagnetic interference, etc. Customers are requested to observe applicable regulations and standards in the design of products.

Fail-Safe Design

Any semiconductor devices have inherently a certain rate of failure. You must protect against injury, damage or loss from such failures by incorporating safety design measures into your facility and equipment such as redundancy, fire protection, and prevention of over-current levels and other abnormal operating conditions.

Precautions Related to Usage of Devices

Cypress semiconductor devices are intended for use in standard applications (computers, office automation and other office equipment, industrial, communications, and measurement equipment, personal or household devices, etc.).

CAUTION: Customers considering the use of our products in special applications where failure or abnormal operation may directly affect human lives or cause physical injury or property damage, or where extremely high levels of reliability are demanded (such as aerospace systems, atomic energy controls, sea floor repeaters, vehicle operating controls, medical devices for life support, etc.) are requested to consult with sales representatives before such use. The company will not be responsible for damages arising from such use without prior approval.

6.2 Precautions for Package Mounting

Package mounting may be either lead insertion type or surface mount type. In either case, for heat resistance during soldering, you should only mount under Cypress's recommended conditions. For detailed information about mount conditions, contact your sales representative.

Lead Insertion Type

Mounting of lead insertion type packages onto printed circuit boards may be done by two methods: direct soldering on the board, or mounting by using a socket.

Direct mounting onto boards normally involves processes for inserting leads into through-holes on the board and using the flow soldering (wave soldering) method of applying liquid solder. In this case, the soldering process usually causes leads to be subjected to thermal stress in excess of the absolute ratings for storage temperature. Mounting processes should conform to Cypress recommended mounting conditions.

If socket mounting is used, differences in surface treatment of the socket contacts and IC lead surfaces can lead to contact deterioration after long periods. For this reason it is recommended that the surface treatment of socket contacts and IC leads be verified before mounting.

Surface Mount Type

Surface mount packaging has longer and thinner leads than lead-insertion packaging, and therefore leads are more easily deformed or bent. The use of packages with higher pin counts and narrower pin pitch results in increased susceptibility to open connections caused by deformed pins, or shorting due to solder bridges.

You must use appropriate mounting techniques. Cypress recommends the solder reflow method, and has established a ranking of mounting conditions for each product. Users are advised to mount packages in accordance with Cypress ranking of recommended conditions.



Lead-Free Packaging

CAUTION: When ball grid array (BGA) packages with Sn-Ag-Cu balls are mounted using Sn-Pb eutectic soldering, junction strength may be reduced under some conditions of use.

Storage of Semiconductor Devices

Because plastic chip packages are formed from plastic resins, exposure to natural environmental conditions will cause absorption of moisture. During mounting, the application of heat to a package that has absorbed moisture can cause surfaces to peel, reducing moisture resistance and causing packages to crack. To prevent, do the following:

- 1. Avoid exposure to rapid temperature changes, which cause moisture to condense inside the product. Store products in locations where temperature changes are slight.
- Use dry boxes for product storage. Products should be stored below 70% relative humidity, and at temperatures between 5°C and 30°C.

When you open Dry Package that recommends humidity 40% to 70% relative humidity.

- 3. When necessary, Cypress packages semiconductor devices in highly moisture-resistant aluminum laminate bags, with a silica gel desiccant. Devices should be sealed in their aluminum laminate bags for storage.
- 4. Avoid storing packages where they are exposed to corrosive gases or high levels of dust.

Baking

Packages that have absorbed moisture may be de-moisturized by baking (heat drying). Follow the Cypress recommended conditions for baking.

Condition: 125°C/24 h

Static Electricity

Because semiconductor devices are particularly susceptible to damage by static electricity, you must take the following precautions:

- 1. Maintain relative humidity in the working environment between 40% and 70%. Use of an apparatus for ion generation may be needed to remove electricity.
- 2. Electrically ground all conveyors, solder vessels, soldering irons and peripheral equipment.
- 3. Eliminate static body electricity by the use of rings or bracelets connected to ground through high resistance (on the level of 1 $M\Omega$).

Wearing of conductive clothing and shoes, use of conductive floor mats and other measures to minimize shock loads is recommended.

- 4. Ground all fixtures and instruments, or protect with anti-static measures.
- 5. Avoid the use of styrofoam or other highly static-prone materials for storage of completed board assemblies.



6.3 Precautions for Use Environment

Reliability of semiconductor devices depends on ambient temperature and other conditions as described above.

For reliable performance, do the following:

1. Humidity

Prolonged use in high humidity can lead to leakage in devices as well as printed circuit boards. If high humidity levels are anticipated, consider anti-humidity processing.

2. Discharge of Static Electricity

When high-voltage charges exist close to semiconductor devices, discharges can cause abnormal operation. In such cases, use anti-static measures or processing to prevent discharges.

3. Corrosive Gases, Dust, or Oil

Exposure to corrosive gases or contact with dust or oil may lead to chemical reactions that will adversely affect the device. If you use devices in such conditions, consider ways to prevent such exposure or to protect the devices.

4. Radiation, Including Cosmic Radiation

Most devices are not designed for environments involving exposure to radiation or cosmic radiation. Users should provide shielding as appropriate.

5. Smoke, Flame

CAUTION: Plastic molded devices are flammable, and therefore should not be used near combustible substances. If devices begin to smoke or burn, there is danger of the release of toxic gases.

Customers considering the use of Cypress products in other special environmental conditions should consult with sales representatives.



7. Handling Devices

Power supply pins

In products with multiple VCC and VSS pins, respective pins at the same potential are interconnected within the device in order to prevent malfunctions such as latch-up. However, all of these pins should be connected externally to the power supply or ground lines in order to reduce electromagnetic emission levels, to prevent abnormal operation of strobe signals caused by the rise in the ground level, and to conform to the total output current rating.

Moreover, connect the current supply source with each Power supply pin and GND pin of this device at low impedance. It is also advisable that a ceramic capacitor of approximately 0.1 µF be connected as a bypass capacitor between each Power supply pin and GND pin near this device.

Stabilizing supply voltage

A malfunction may occur when the power supply voltage fluctuates rapidly even though the fluctuation is within the recommended operating conditions of the VCC power supply voltage. As a rule, with voltage stabilization, suppress the voltage fluctuation so that the fluctuation in VCC ripple (peak-to-peak value) at the commercial frequency (50 Hz/60 Hz) does not exceed 10% of the VCC value in the recommended operating conditions, and the transient fluctuation rate does not exceed 0.1 V/µs when there is a momentary fluctuation on switching the power supply.

Crystal Oscillator Circuit

Noise near the X0/X1 and X0A/X1A pins may cause the device to malfunction. Design the printed circuit board so that X0/X1, X0A/X1A pins, the crystal oscillator (or ceramic oscillator), and the bypass capacitor to ground are located as close to the device as possible.

It is strongly recommended that the PC board artwork be designed such that the X0/X1 and X0A/X1A pins are surrounded by ground plane as this is expected to produce stable operation.

Evaluate oscillation of your using crystal oscillator by your mount board.

Sub Crystal Oscillator

This series sub oscillator circuit is low gain to keep the low current consumption. The crystal oscillator to fill the following conditions is recommended for sub crystal oscillator to stabilize the oscillation.

Surface mount type	
Size:	More than 3.2 mm × 1.5 mm
Load capacitance:	Approximately 6 pF to 7 pF
■Lead type	

Lead type

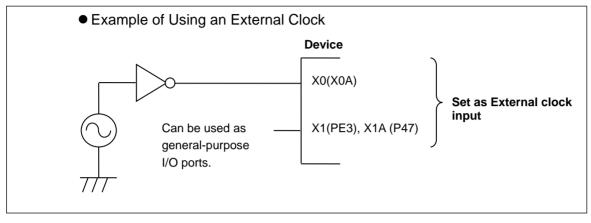
Load capacitance: Approximately 6 pF to 7 pF



Using an External Clock

When using an external clock as an input of the main clock, set X0/X1 to the external clock input, and input the clock to X0. X1(PE3) can be used as a general-purpose I/O port.

Similarly, when using an external clock as an input of the sub clock, set X0A/X1A to the external clock input, and input the clock to X0A. X1A (P47) can be used as a general-purpose I/O port.



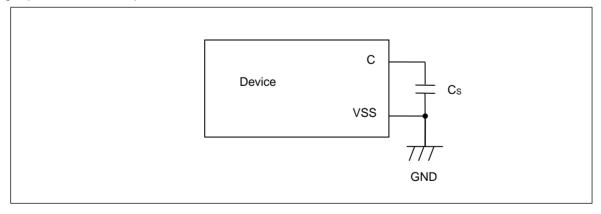
Handling when Using Multi-Function Serial Pin as I²C Pin

If it is using the multi-function serial pin as I²C pins, P-ch transistor of digital output is always disabled. However, I²C pins need to keep the electrical characteristic like other pins and not to connect to the external I²C bus system with power OFF.

C Pin

This series contains the regulator. Be sure to connect a smoothing capacitor (C_s) for the regulator between the C pin and the GND pin. Please use a ceramic capacitor or a capacitor of equivalent frequency characteristics as a smoothing capacitor. However, some laminated ceramic capacitors have the characteristics of capacitance variation due to thermal fluctuation (F characteristics and Y5V characteristics). Please select the capacitor that meets the specifications in the operating conditions to use by evaluating the temperature characteristics of a capacitor.

A smoothing capacitor of about 4.7 µF would be recommended for this series.



Mode Pins (MD0)

Connect the MD pin (MD0) directly to VCC or VSS pins. Design the printed circuit board such that the pull-up/down resistance stays low, as well as the distance between the mode pins and VCC pins or VSS pins is as short as possible and the connection impedance is low, when the pins are pulled-up/down such as for switching the pin level and rewriting the Flash memory data. It is because of preventing the device erroneously switching to test mode due to noise.



Notes on Power-on

Turn power on/off in the following order or at the same time.

Turning on : VCC \rightarrow AVCC \rightarrow AVRH Turning off : AVRH \rightarrow AVCC \rightarrow VCC

Serial Communication

There is a possibility to receive wrong data due to the noise or other causes on the serial communication. Therefore, design a printed circuit board so as to avoid noise.

Consider the case of receiving wrong data due to noise, perform error detection such as by applying a checksum of data at the end. If an error is detected, retransmit the data.

Differences in Features among the Products with Different Memory Sizes and between Flash Products and MASK Products

The electric characteristics including power consumption, ESD, latch-up, noise characteristics, and oscillation characteristics among the products with different memory sizes and between Flash products and MASK products are different because chip layout and memory structures are different.

If you are switching to use a different product of the same series, please make sure to evaluate the electric characteristics.

Pull-Up Function of 5V Tolerant I/O

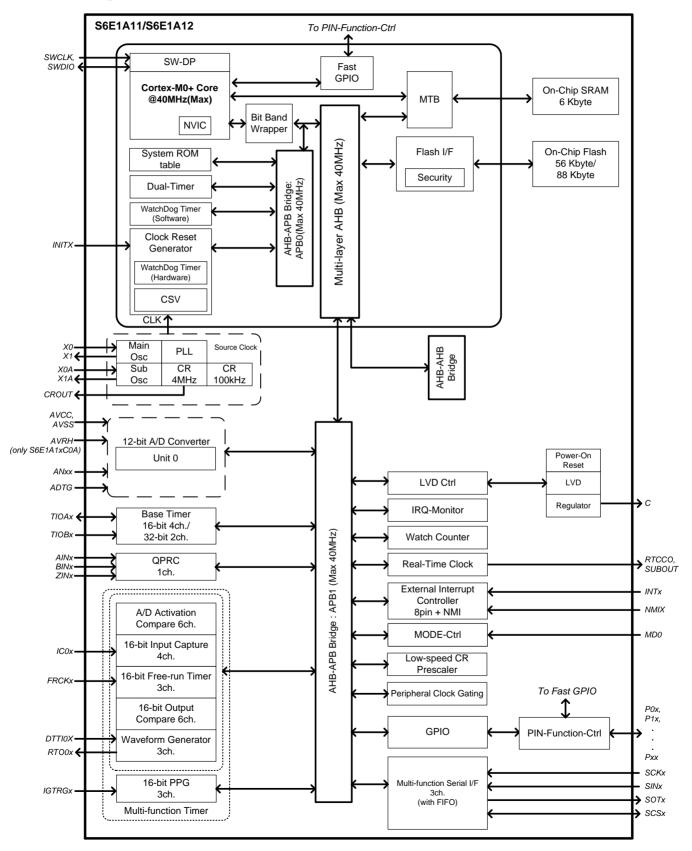
Please do not input the signal more than VCC voltage at the time of Pull-Up function use of 5V tolerant I/O.

Handling when using debug pins

When debug pins (SWDIO/SWCLK) are set to GPIO or other peripheral functions, only set them as output, do not set them as input.



8. Block Diagram



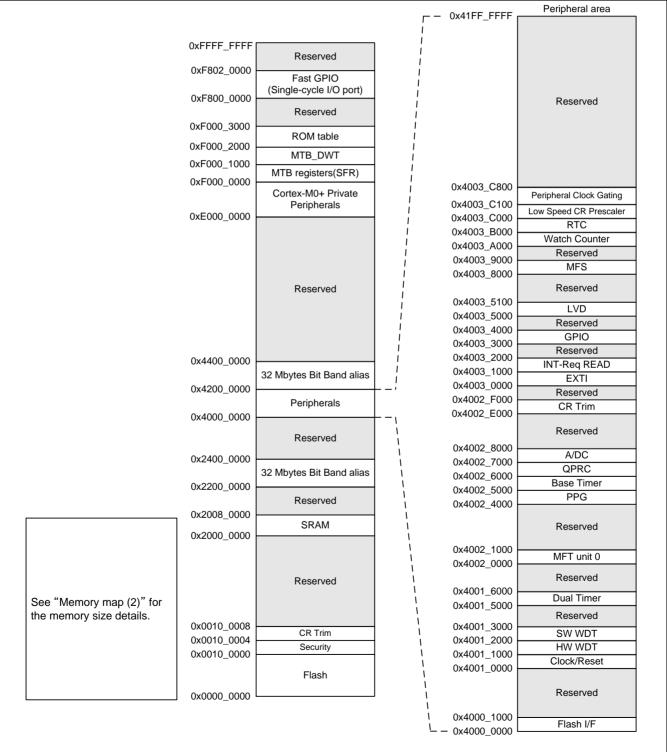


9. Memory Size

See Memory size in 1. Product Lineup to confirm the memory size.

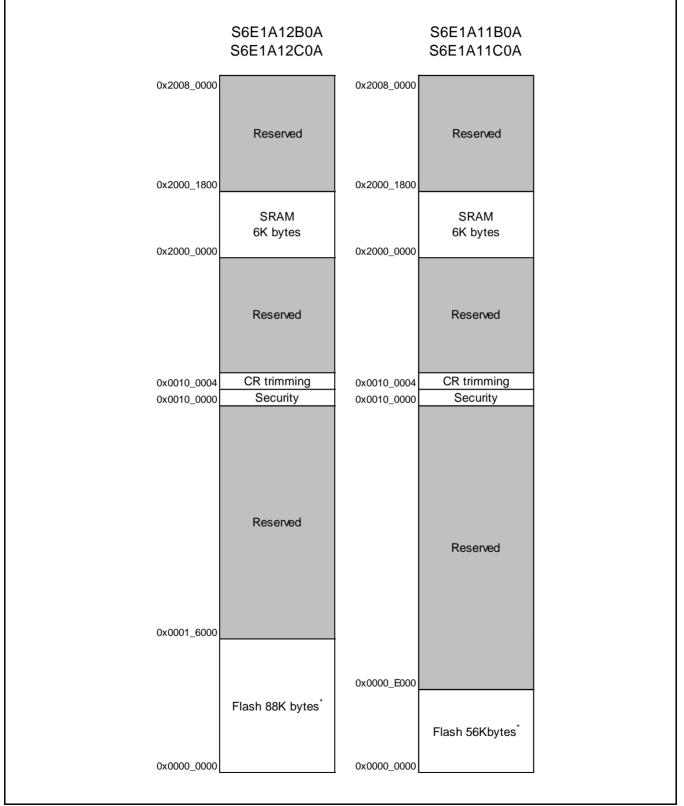
10. Memory Map

Memory Map (1)





Memory Map (2)



*: See "S6E1A1 Series Flash Programming Manual" to check details of the flash memory.



Peripheral Address Map

Start address	End address	Bus	Peripheral			
0x4000_0000	0x4000_0FFF		Flash memory I/F register			
0x4000_1000	0x4000_FFFF	АНВ	Reserved			
0x4001_0000	0x4001_0FFF		Clock/Reset Control			
0x4001_1000	0x4001_1FFF		Hardware Watchdog Timer			
0x4001_2000	0x4001_2FFF	APB0	Software Watchdog Timer			
0x4001_3000	0x4001_4FFF	APDU	Reserved			
0x4001_5000	0x4001_5FFF		Dual-Timer			
0x4001_6000	0x4001_FFFF		Reserved			
0x4002_0000	0x4002_0FFF		Multi-function Timer unit0			
0x4002_1000	0x4002_3FFF		Reserved			
0x4002_4000	0x4002_4FFF		PPG			
0x4002_5000	0x4002_5FFF		Base Timer			
0x4002_6000	0x4002_6FFF		Quadrature Position/Revolution Counter			
0x4002_7000	0x4002_7FFF		A/D Converter			
0x4002_8000	0x4002_DFFF		Reserved			
0x4002_E000	0x4002_EFFF		Built-in CR trimming			
0x4002_F000	0x4002_FFFF		Reserved			
0x4003_0000	0x4003_0FFF		External Interrupt Controller			
0x4003_1000	0x4003_1FFF		Interrupt Request Batch-Read Function			
0x4003_2000	0x4003_2FFF	APB1	Reserved			
0x4003_3000	0x4003_3FFF		GPIO			
0x4003_4000	0x4003_4FFF		Reserved			
0x4003_5000	0x4003_57FF		Low-Voltage Detection			
0x4003_5800	0x4003_7FFF		Reserved			
0x4003_8000	0x4003_8FFF		Multi-function Serial Interface			
0x4003_9000	0x4003_9FFF		Reserved			
0x4003_A000	0x4003_AFFF		Watch Counter			
0x4003_B000	0x4003_BFFF		Real-time clock			
0x4003_C000	0x4003_C0FF]	Low-speed CR Prescaler			
0x4003_C100	0x4003_C7FF		Peripheral Clock Gating			
0x4003_C800	0x4003_FFFF		Reserved			
0x4004_0000	0x41FF_FFFF	AHB	Reserved			



11. Pin Status in Each CPU State

The terms used for pin status have the following meanings.

■INITX=0

This is the period when the INITX pin is the L level.

■INITX=1

This is the period when the INITX pin is the H level.

■SPL=0

This is the status that the standby pin level setting bit (SPL) in the standby mode control register (STB_CTL) is set to 0.

■SPL=1

This is the status that the standby pin level setting bit (SPL) in the standby mode control register (STB_CTL) is set to 1.

■Input enabled

Indicates that the input function can be used.

Internal input fixed at 0

This is the status that the input function cannot be used. Internal input is fixed at L.

■Hi-Z

Indicates that the pin drive transistor is disabled and the pin is put in the Hi-Z state.

Setting disabled

Indicates that the setting is disabled.

■Maintain previous state

Maintains the state that was immediately prior to entering the current mode. If a built-in peripheral function is operating, the output follows the peripheral function. If the pin is being used as a port, that output is maintained.

■Analog input is enabled

Indicates that the analog input is enabled.



List of Pin Status

Pin status type	Function group	State upon power-on reset or low-voltage detection	State at INITX input	State upon device internal reset	State in Run mode or SLEEP mode	RTC m	MER mode, lode, or mode
^o in sta		Power supply unstable		pply stable	Power supply stable		pply stable
		-	INITX = 0	INITX = 1	INITX = 1		X = 1
	GPIO selected	- Setting disabled	- Setting disabled	- Setting disabled	- Maintain previous state	SPL = 0 Maintain previous state	SPL = 1 Hi-Z / Internal input fixed at "0"
A	Main crystal oscillator input pin/ External main clock input selected	Input enabled	Input enabled	Input enabled	Input enabled	Input enabled	Input enabled
	GPIO selected	Setting disabled	Setting disabled	Setting disabled	Maintain previous state	Maintain previous state	Hi-Z / Internal input fixed at "0"
	External main clock input selected	Setting disabled	Setting disabled	Setting disabled	Maintain previous state	Maintain previous state	Hi-Z / Internal input fixed at "0"
В	Main crystal oscillator output pin	Hi-Z / Internal input fixed at "0"/ Input enabled	Hi-Z / Internal input fixed at "0"	Hi-Z / Internal input fixed at "0"	Maintain previous state/When oscillation stops* ¹ , Hi-Z / Internal input fixed at "0"	Maintain previous state/When oscillation stops*1, Hi-Z / Internal input fixed at "0"	Maintain previous state/When oscillation stops*1, Hi-Z / Internal input fixed at "0"
С	INITX input pin	Pull-up / Input enabled	Pull-up / Input enabled	Pull-up / Input enabled	Pull-up / Input enabled	Pull-up / Input enabled	Pull-up / Input enabled
D	Mode input pin	Input enabled	Input enabled	Input enabled	Input enabled	Input enabled	Input enabled
	GPIO selected	Setting disabled	Setting disabled	Setting disabled	Maintain previous state	Maintain previous state	Hi-Z / Internal input fixed at "0"
E	Sub crystal oscillator input pin / External sub clock input selected	Input enabled	Input enabled	Input enabled	Input enabled	Input enabled	Input enabled



Pin status type	Function group	State upon power-on reset or low-voltage detection	State at INITX input	State upon device internal reset	State in Run mode or SLEEP mode	RTC m	MER mode, lode, or mode
^o in sta		Power supply unstable		pply stable	Power supply stable		pply stable
		-	INITX = 0	INITX = 1	INITX = 1		X = 1
	GPIO selected	- Setting disabled	- Setting disabled	- Setting disabled	- Maintain previous state	SPL = 0 Maintain previous state	SPL = 1 Hi-Z / Internal input fixed at "0"
	External sub clock input selected	Setting disabled	Setting disabled	Setting disabled	Maintain previous state	Maintain previous state	Hi-Z / Internal input fixed at "0"
F	Sub crystal oscillator output pin	Hi-Z / Internal input fixed at "0"/ Input enabled	Hi-Z / Internal input fixed at "0"	Hi-Z / Internal input fixed at "0"	Maintain previous state	Maintain previous state/When oscillation stops* ² , Hi-Z / Internal input fixed at "0"	Maintain previous state/When oscillation stops* ² , Hi-Z / Internal input fixed at "0"
	NMIX selected	Setting disabled	Setting disabled	Setting disabled			Maintain previous state
G	Resource other than the above selected	Hi-Z	Hi-Z / Input	Hi-Z / Input enabled	Maintain previous state	Maintain previous state	Hi-Z / Internal input fixed at
	GPIO selected		enabled	input onubiou			"0"
Н	Serial wire debug selected	Hi-Z	Pull-up / Input enabled	Pull-up / Input enabled	Maintain	Maintain	Maintain previous state
	GPIO selected	Setting disabled	Setting disabled	Setting disabled	previous state	previous state	Hi-Z / Internal input fixed at "0"
I	Resource selected	Hi-Z	Hi-Z / Input	Hi-Z / Input enabled	Maintain previous state	Maintain previous state	Hi-Z / Internal input fixed at
	GPIO selected		enabled	input enabled	previous state	previous state	"0"
	External interrupt enabled selected	Setting disabled	Setting disabled	Setting disabled			Maintain previous state
J	Resource other than the above selected	Hi-Z	Hi-Z / Input enabled	Hi-Z / Input enabled	Maintain previous state	Maintain previous state	Hi-Z / Internal input fixed at "0"
	GPIO selected		5105100				Ŭ I
к	Analog input selected	Hi-Z	Hi-Z / Internal input fixed at "0" / Analog input enabled	Hi-Z / Internal input fixed at "0" / Analog input enabled			
	Resource other than the above selected	Setting	Setting	Setting	Maintain	Maintain	Hi-Z / Internal input fixed at
	GPIO selected	disabled	disabled	disabled	previous state	previous state	"O'"



status type	Function group	State upon power-on reset or low-voltage detection	State at INITX input	State upon device internal reset	State in Run mode or SLEEP mode	RTC m	MER mode, lode, or ' mode
Pin sta		Power supply unstable	Power supply stable		Power supply stable	Power su	oply stable
1		-	INITX = 0	INITX = 1	INITX = 1		X = 1
		-	-	-	-	SPL = 0	SPL = 1
	Analog input selected	Hi-Z	Hi-Z / Internal input fixed at "0" / Analog input enabled				
L	External interrupt enabled selected						Maintain previous state
	Resource other than the above selected	Setting disabled	Setting disabled	Setting disabled	Maintain previous state	Maintain previous state	Hi-Z / Internal input fixed at
	GPIO selected						"0"

*1:Oscillation stops in Sub timer mode, Low-speed CR timer mode, STOP mode, RTC mode.

*2:Oscillation stops in STOP mode.



12. Electrical Characteristics

12.1 Absolute Maximum Ratings

Parameter	Symbol		Rating	Unit	Remarks
	Symbol	Min	Max		Rellial K5
Power supply voltage*1, *2	Vcc	Vss - 0.5	Vss + 6.5	V	
Analog power supply voltage* ^{1, *3}	AVcc	Vss - 0.5	Vss + 6.5	V	
Analog reference voltage*1, *3	AVRH	V _{SS} - 0.5	Vss + 6.5	V	Only S6E1A1xC0A
Input voltage*1	VI	V _{SS} - 0.5	V _{CC} + 0.5 (≤ 6.5 V)	V	
		Vss - 0.5	Vss + 6.5	V	5V tolerant
Analog pin input voltage*1	VIA	V _{SS} - 0.5	AV _{CC} + 0.5 (≤ 6.5 V)	V	
Output voltage*1	Vo	V _{SS} - 0.5	Vcc + 0.5 (≤ 6.5 V)	V	
			10	mA	4 mA type
"L" level maximum output current*4	lo∟	-	20	mA	12 mA type
"I " I +			4	mA	4 mA type
"L" level average output current*5	Iolav	-	12	mA	12 mA type
"L" level total maximum output current	Σlol	-	100	mA	
"L" level total average output current*6	ΣIOLAV	-	50	mA	
			- 10	mA	4 mA type
"H" level maximum output current*4	I _{OH}	-	- 20	mA	12 mA type
ини I I I I I I I I I I I I I I I I I I			- 4	mA	4 mA type
"H" level average output current*5	Iohav	-	- 12	mA	12 mA type
"H" level total maximum output current	∑Іон	-	- 100	mA	
"H" level total average output current*6	ΣΙοήαν	-	- 50	mA	
Power consumption	PD	-	200	mW	
Storage temperature	T _{STG}	- 55	+ 150	°C	

*1:These parameters are based on the condition that $V_{SS} = AVss = 0$ V.

*2:Vcc must not drop below Vss - 0.5 V.

*3:Ensure that the voltage does not to exceed V_{CC} + 0.5 V at power-on.

*4:The maximum output current is the peak value for a single pin.

*5:The average output is the average current for a single pin over a period of 100 ms.

*6:The total average output current is the average current for all pins over a period of 100 ms.

Warning

• Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of absolute maximum ratings. Do not exceed these ratings



 $(V_{SS} = AV_{SS} = 0.0V)$

12.2 Recommended Operating Conditions

Value Parameter Symbol Conditions Unit Remarks Min Max Power supply voltage Vcc 2.7*2 V 5.5 -Analog power supply voltage **AVcc** -2.7 5.5 V AVcc = VccOnly Analog reference voltage AVRH 2.7 **AVcc** V _ S6E1A1xC0A Smoothing capacitor Cs 1 10 μF For regulator*1 _ Operating temperature Та _ - 40 +105°C

"1: See "C Pin" in "6. Handling Precautions" for the connection of the smoothing capacitor.

*2: In between less than the minimum power supply voltage and low voltage reset/interrupt detection voltage or more, instruction execution and low voltage detection function by built-in High-speed CR(including Main PLL is used) or built-in Low-speed CR is possible to operate only.

Warning

- 1. The recommended operating conditions are required in order to ensure the normal operation of the semiconductor device. All of the device's electrical characteristics are warranted when the device is operated within these ranges.
- 2. Always use semiconductor devices within their recommended operating condition ranges. Operation outside these ranges may adversely affect reliability and could result in device failure.
- 3. No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet.
- 4. Users considering application outside the listed conditions are advised to contact their representatives beforehand.



12.3 DC Characteristics

12.3.1 Current Rating

Symbol		HCLK	Va	lue		Pomarks	
(Pin name)		Conditions	Frequency *4	Typ*¹	Max* ²	Unit	Remarks
		4MHz external clock input, PLL	4MHz	0.7	1.5		
		ON*8	8MHz	1.3	2.3		
		NOP code executed	20MHz	2.8	4.0	mA	*3
		Built-in high speed CR stopped All peripheral clock stopped by CKENx	40MHz	5.7	7.3	-	
	Run mode,	4MHz external clock input, PLL	4MHz	0.6	1.4		
	code executed	ON*8	8MHz	1.2	2.1		
	from Flash	Benchmark code executed	20MHz	2.6	3.7	mA	*3
		Built-in high speed CR stopped PCLK1 stopped	40MHz	4.8	6.3		
		4MHz crystal oscillation, PLL ON*8	4MHz	1.0	2.9		
		NOP code executed	8MHz	1.7	3.6		*3
		Built-in high speed CR stopped	20MHz	3.4	5.6	mA	
		All peripheral clock stopped by	40MHz	5.7	8.2	_	
		CKENx					
		4MHz external clock input, PLL ON*8	4MHz 8MHz	0.5	1.2		
	Run mode,	iun mode, NOP code executed		0.9	1.8		
lcc	code executed	Built-in high speed CR stopped	20MHz	2.0	2.9	mA	*3
(VCC)	from RAM	All peripheral clock stopped by CKENx	40MHz	3.7	4.8		
	Run mode, code executed from Flash	4MHz external clock input, PLL ON NOP code executed Built-in high speed CR stopped PCLK1 stopped	40MHz	2.8	3.7	mA	*3,*6,*7
		Built-in high speed CR*5 NOP code executed All peripheral clock stopped by CKENx	4MHz	0.8	1.5	mA	*3
	Run mode, code executed from Flash	32kHz crystal oscillation NOP code executed All peripheral clock stopped by CKENx	32kHz	65	900	μA	*3
		Built-in low speed CR NOP code executed All peripheral clock stopped by CKENx	100kHz	73	920	μΑ	*3
		4MHz external clock input, PLL	4MHz	0.4	1.2		
		ON* ⁸	8MHz	0.7	1.6	mA	*3
		All peripheral clock stopped by	20MHz	1.5	2.4		Ŭ
		CKENx	40MHz	2.7	3.7		
lccs (VCC)	SLEEP operation	Built-in high speed CR* ⁵ All peripheral clock stopped by CKENx	4MHz	0.5	1.2	mA	*3
		32kHz crystal oscillation All peripheral clock stopped by CKENx	32kHz	63	880	μA	*3
		Built-in low speed CR All peripheral clock stopped by CKENx	100kHz	66	890	μA	*3



- *1 : Ta=+25°C,Vcc=3.0V
- *2 : Ta=+105°C,Vcc=5.5V
- *3 : All ports are fixed
- *4 : PCLK0=HCLK/8
- *5 : The frequency is set to 4MHz by trimming *6 : Flash sync down is set to FRWTR.RWT = 11 and FSYNDN.SD = 1111
- *7 : Vcc=2.7V
- *8 : When HCLK=4MHz, PLL OFF

Symbol				alue	Uni	
(Pin name)		Conditions	Тур	Max	t	Remarks
		Ta=25°C Vcc=3.0V LVD off	5.6	28	μΑ	*1
I _{ССН} (VCC)	STOP mode	Ta=25°C Vcc=5.0V LVD off	6.7	30	μA	*1
		Ta=105°C Vcc=5.5V LVD off	-	540	μΑ	*1
	Sub timer mode	Ta=25°C Vcc=3.0V 32kHz crystal oscillation LVD off	12	42	μA	*1
I _{ССТ} (VCC)		Ta=25°C Vcc=5.0V 32kHz crystal oscillation LVD off	13	44	μA	*1
		Ta=105°C Vcc=5.5V 32kHz crystal oscillation LVD off	-	730	μA	*1
		Ta=25°C Vcc=3.0V 32kHz crystal oscillation LVD off	9	36	μA	*1
I _{CCR} (VCC)	RTC mode	Ta=25°C Vcc=5.0V 32kHz crystal oscillation LVD off	10	38	μA	*1
		Ta=105°C Vcc=5.5V 32kHz crystal oscillation LVD off	-	570	μA	*1

*1:All ports are fixed.



LVD current

(V_{CC} = 2.7V to 5.5V, V_{SS} = AV_{SS} = 0V, Ta = - 40°C to + 105°C)

Parameter	Symbol	Pin name	Conditions -	Value		Unit	Remarks	
Farameter				Тур	Max	Unit	Remarks	
Low-Voltage detection circuit		NCC	At operation	0.13	0.3	μA	For occurrence of reset	
(LVD) power supply current	ICCLVD	VCC		0.13	0.3	μA	For occurrence of interrupt	

Flash memory current

(V_{CC} = 2.7V to 5.5V, V_{SS} = AV_{SS} = 0V, Ta = - 40°C to + 105°C)

Parameter	Symbol	Pin name	Conditions	Value		Unit	Remarks	
				Тур	Max	Unit	Reillarks	
Flash memory write/erase current	Iccflash	VCC	At Write/Erase	9.5	11.2	mA		

A/D convertor current (S6E1A1xC0A)

(V_{CC} = 2.7V to 5.5V, V_{SS} = AV_{SS} = 0V, Ta = - 40°C to + 105°C)

Parameter	Symbol	Pin	Conditions	Va	lue	Unit	Remarks
Faranielei	Symbol	name	Conditions	Тур	Max	Onit	Reillarks
Power supply	lagua	AVCC	At operation	0.7	0.9	mA	
current	ICCAD	AVCC	At stop	0.13	13	μA	
Reference power supply	Iccavrh		At operation	1.1	1.97	mA	AVRH=5.5V
current (AVRH)		AVRH	At stop	0.1	1.7	μA	

A/D convertor current (S6E1A1xB0A)

 $(V_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = 0V, Ta = -40^{\circ}C \text{ to } + 105^{\circ}C)$

Parameter	Symbol	Pin	Conditions	Value		Unit	Remarks	
		name	Conditions	Тур	Max	Unit	Remarks	
Power supply	I _{CCAD}	AVCC	At operation	1.8	2.87	mA		
current		AVCC	At stop	0.23	14.7	μA		

Peripheral current dissipation

Clock	Peripheral	Conditions		Frequen	icy (MHz)	Unit	Remarks
system	renpheral	Conditions	4	8	20	40	Onic	Remarks
HCLK	GPIO	At all ports operation	0.11	0.22	0.55	1.10	mA	
	Base timer	At 4ch operation	0.03	0.05	0.15	0.30		
	Multi-functional timer/PPG	At 1unit/4ch operation	0.14	0.28	0.68	1.38		
PCLK1	Quadrature position/Revolution counter	At 1unit operation	0.02	0.04	0.11	0.22	mA	
	ADC	At 1unit operation	0.07	0.14	0.37	0.73		
	Multi-function serial	At 1ch operation	0.15	0.31	0.77	1.54		



12.3.2 Pin Characteristics

Parameter	Symbol	Pin name	Conditions		Value		Unit	Remarks
randiteter	Cymbol		Conditions	Min	Тур	Max	Onic	Remarks
"H" level input voltage (hysteresis	Vihs	CMOS hysteresis input pin, MD0, PE0	-	Vcc × 0.8	-	Vcc + 0.3	V	
input)		5V tolerant input pin	-	Vcc × 0.8	-	V _{SS} + 5.5	V	
"L" level input voltage (hysteresis	VILS	CMOS hysteresis input pin, MD0, PE0	-	V _{SS} - 0.3	-	Vcc × 0.2	V	
input)		5V tolerant input pin	-	Vss - 0.3	-	Vcc × 0.2	V	
"H" level		4 mA type	$V_{CC} \ge 4.5 V,$ $I_{OH} = -4 mA$ $V_{CC} < 4.5 V,$ $I_{OH} = -2 mA$	_ Vcc - 0.5	-	Vcc	V	
output voltage	Vон	12 mA type	$V_{CC} \ge 4.5 V,$ $I_{OH} = -12 mA$ $V_{CC} < 4.5 V,$ $I_{OH} = -8 mA$	- V _{CC} - 0.5	-	V _{cc}	V	
"L" level	Vol	4 mA type	$V_{CC} \ge 4.5 \text{ V},$ $I_{OL} = 4 \text{ mA}$ $V_{CC} < 4.5 \text{ V},$ $I_{OL} = 2 \text{ mA}$	Vss	-	0.4	V	
output voltage	VOL	12 mA type	$V_{CC} \ge 4.5 V,$ $I_{OL} = 12 mA$ $V_{CC} < 4.5 V,$ $I_{OL} = 8 mA$	- V _{SS}	-	0.4	v	
Input leak current	lı∟	-	-	- 5	-	+ 5	μA	
Pull-up resistance	Rpu	Pull-up pin	V _{CC} ≥ 4.5 V	33	50	90	kΩ	
value	INPU		Vcc < 4.5 V	-	-	180	1/22	
Input capacitance	Cin	Other than VCC, VSS, AVCC, AVSS, AVRH	-	-	5	15	pF	

(V_{CC} =AV_{CC} = 2.7 V to 5.5 V, V_{SS} = AV_{SS} = 0 V, Ta = - 40°C to + 105°C)



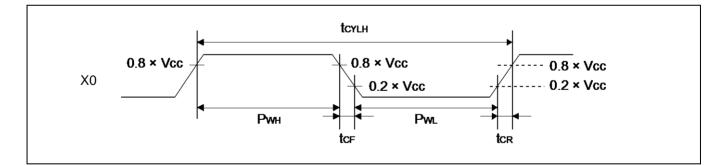
12.4 AC Characteristics

12.4.1 Main Clock Input Characteristics

Devenueter	Cumhal	Pin	Conditions	V	alue	11	Remarks
Parameter	Symbol	name	Conditions	Min	Max	Unit	Remarks
			V _{CC} ≥ 4.5V	4	40	MHz	When the crystal
logut fraguanay	Есн		$V_{CC} < 4.5V$	4	20		oscillator is connected
Input frequency	ГСН		-	4	40 MHz clock is used		When the external clock is used
Input clock cycle	tсүгн	X0, X1	-	25	250	ns	When the external clock is used
Input clock pulse width	-		Pwh/tcylh, Pwl/tcylh	45	55	%	When the external clock is used
Input clock rising time and falling time	t _{CF,} t _{CR}		-	-	5	ns	When the external clock is used
	Fсм	-	-	-	41.2	MHz	Master clock
Internal operating	Fcc	-	-	-	41.2	MHz	Base clock (HCLK/FCLK)
clock ^{*1} frequency	F _{CP0}	-	-	-	41.2	MHz	APB0 bus clock*2
	F _{CP1}	-	-	-	41.2	MHz	APB1 bus clock*2
laternel en eretin -	t _{cycc}	-	-	24.27	-	ns	Base clock (HCLK/FCLK)
Internal operating clock ^{*1} cycle time	t _{CYCP0}	-	-	24.27	-	ns	APB0 bus clock*2
	t _{CYCP1}	-	-	24.27	-	ns	APB1 bus clock*2

*1: For details of each internal operating clock, refer to "CHAPTER: Clock" in "FM0+ Family PERIPHERAL MANUAL".

*2: For details of the APB bus to which a peripheral is connected, see "8. Block Diagram".

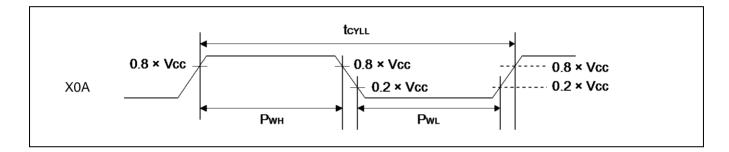




12.4.2 Sub Clock Input Characteristics

	-	1	(Vo	cc = AVcc		5.5 V, Vss	= AV _{SS} =	0 V, Ta = - 40°C to + 10	
Parameter	Symbol	Pin	Conditions	Value			Unit	Remarks	
Falameter	Symbol	name	Conditions	Min	Тур	Max	Unit	itema ka	
Input frequency	1/t _{CYLL}		-	-	32.768	-	kHz	When the crystal oscillator is connected	
		X0A, X1A	-	32	-	100	kHz	When the external clock is used	
Input clock cycle	tCYLL		-	10	-	31.25	μs	When the external clock is used	
Input clock pulse width	-		PWH/tCYLL, PWL/tCYLL	45	-	55	%	When the external clock is used	

*: See "Sub crystal oscillator" in "7. Handling Devices" for the crystal oscillator used.





12.4.3 Built-in CR Oscillation Characteristics

Built-in high-speed CR

Demonstration	0 milest	O a maliti a ma		Value		11	Damarka	
Parameter	Symbol	Conditions	Min	Тур	Max	Unit	Remarks	
		Ta = + 25°C, 3.6V < V _{CC} ≤ 5.5V	3.92	4	4.08			
		Ta =0°C to + 85°C, 3.6V < V _{CC} ≤ 5.5V	3.9	4	4.1			
		Ta = - 40°C to + 105°C, 3.6V < V _{CC} ≤ 5.5V	3.88	4	4.12		During trimming*1	
Clock frequency	FCRH	Ta = + 25°C, 2.7V ≤ V _{CC} ≤ 3.6V	3.94	4	4.06	MHz		
		Ta = -20° C to $+85^{\circ}$ C, 2.7V $\leq V_{CC} \leq 3.6$ V	3.92	4	4.08			
		Ta = - 20°C to + 105°C, 2.7V ≤ V _{CC} ≤ 3.6V	3.9	4	4.1			
		Ta = - 40°C to + 105°C, 2.7V \leq V _{CC} \leq 3.6V	3.88	4	4.12			
		Ta = - 40°C to + 105°C	2.8	4	5.2		Not during trimming	
Frequency stabilization time	t _{CRWT}	-	-	-	30	μs	*2	

*1: In the case of using the values in CR trimming area of Flash memory at shipment for frequency trimming/temperature trimming.

*2: This is time from the trim value setting to stable of the frequency of the High-speed CR clock. After setting the trim value, the period when the frequency stability time passes can use the High-speed CR clock as a source clock.

Built-in low-speed CR

 $(V_{CC} = AV_{CC} = 2.7 \text{ V to } 5.5 \text{ V}, V_{SS} = AV_{SS} = 0 \text{ V}, \text{ Ta} = -40^{\circ}\text{C to} + 105^{\circ}\text{C})$

(V_{CC} = AV_{CC} = 2.7 V to 5.5 V, V_{SS} = AV_{SS} = 0 V, Ta = - 40°C to + 105°C)

Parameter	Symbol	Conditions		ValueUnitRemarksTypMaxItematical constraints100150kHz	Pomarke		
Faialletei	Symbol	Conditions	Min	Тур	Max	Onit	Reillaiks
Clock frequency	F _{CRL}	-	50	100	150	kHz	



12.4.4 Operating Conditions of Main PLL

(In the case of using the main clock as the input clock of the PLL)

(V_{CC} = AV_{CC} = 2.7 V to 5.5 V, V_{SS} = AV_{SS} = 0 V, Ta = - 40°C to + 105°C)

Parameter	Symbol		Value		Unit	Remarks
Falanielei	Symbol	Min	Тур	Max	Onic	Rellidiks
PLL oscillation stabilization wait time*1 (LOCK UP time)	tlock	100	-	-	μs	
PLL input clock frequency	Fplli	4	-	16	MHz	
PLL multiple rate	-	5	-	37	multiple	
PLL macro oscillation clock frequency	FPLLO	75	-	150	MHz	
Main PLL clock frequency*2	FCLKPLL	-	-	40	MHz	

*1: The wait time is the time it takes for PLL oscillation to stabilize.

*2: For details of the main PLL clock (CLKPLL), refer to "CHAPTER: Clock" in "FM0+ Family PERIPHERAL MANUAL".

12.4.5 Operating Conditions of Main PLL

(In the case of using the built-in high-speed CR clock as the input clock of the main PLL)

(Vcc = AVcc = 2.7 V to 5.5 V, Vss = AVss = 0 V, Ta = - 40°C to + 105°C)

Parameter	Symbol	Value			Unit	Remarks
Falameter	Symbol	Min	Тур	Max	Unit	Reillarks
PLL oscillation stabilization wait time*1 (LOCK UP time)	tlock	100	-	-	μs	
PLL input clock frequency	Fplli	3.88	4	4.12	MHz	
PLL multiple rate	-	19	-	35	multiple	
PLL macro oscillation clock frequency	F _{PLLO}	72	-	150	MHz	
Main PLL clock frequency*2	FCLKPLL	-	-	41.2	MHz	

*1: The wait time is the time it takes for PLL oscillation to stabilize.

*2: For details of the main PLL clock (CLKPLL), refer to "CHAPTER: Clock" in "FM0+ Family PERIPHERAL MANUAL".

Note:

For the main PLL source clock, input the high-speed CR clock (CLKHC) whose frequency has been trimmed.



12.4.6 Reset Input Characteristics

			(Vcc =AV	/cc = 2.7 V to 5.2	5 V, Vss = AVss	= 0 V, Ta =	= - 40°C to + 10	5°C
Parameter	Symbol	Pin	Conditions	Va	lue	Unit	Remarks	
i arameter	Cymbol	name	Conditions	Min	Max	Onic	Remarks	
Reset input time	tinitx	INITX	-	500	-	ns		

12.4.7 Power-on Reset Timing

 $(V_{SS} = 0 V, Ta = -40^{\circ}C to + 105^{\circ}C)$

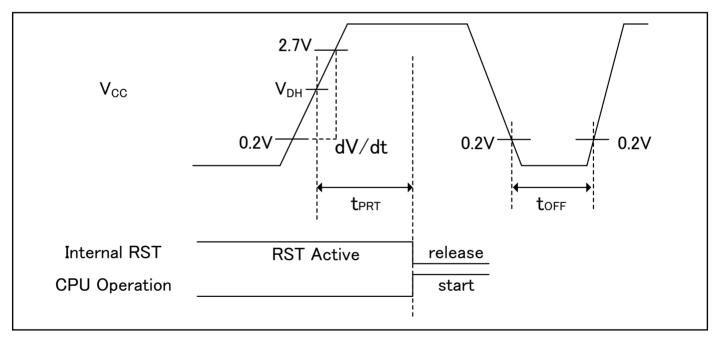
Parameter	Symbol	Pin	Conditions		Value		Unit	Remark
Farameter	Symbol	name	Conditions	Min	Тур	Max	Onit	Remark
Power supply shout down time	t _{OFF}			1	-	-	ms	*1
Power ramp rate	dV/dt	VCC	Vcc: 0.2V to 2.70V	1.0	-	1000	mV/µs	*2
Time until releasing Power-on reset	t PRT			0.43	-	3.4	ms	

*1: VCC must be held below 0.2V for minimum period of tOFF. Improper initialization may occur if this condition is not met.

*2: This dV/dt characteristic is applied at the power-on of cold start (toff>1ms).

Note:

- If toFF cannot be satisfied designs must assert external reset(INITX) at power-up and at any brownout event per 12.4.6.



Glossary

UDH: detection voltage of Low Voltage detection reset. See "12.6. Low-Voltage Detection Characteristics".

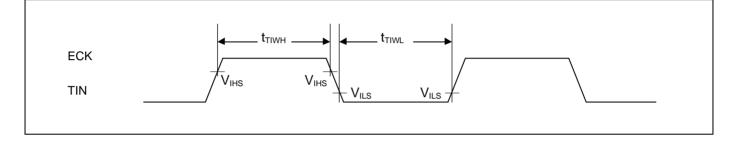


12.4.8 Base Timer Input Timing

Timer input timing

 $(V_{CC} = AV_{CC} = 2.7 \text{ V to } 5.5 \text{ V}, V_{SS} = AV_{SS} = 0 \text{ V}, \text{ Ta} = -40^{\circ}\text{C to} + 105^{\circ}\text{C})$

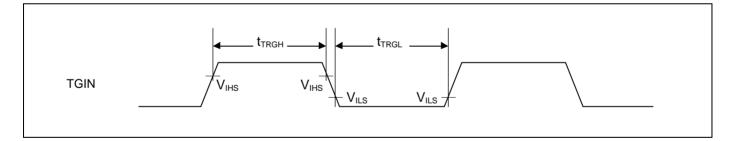
Parameter	Symbol	Pin name	Conditions	Va	ue	Unit	Remarks
Falameter	Symbol	Finitianie	Conditions	Min	Max	Unit	Relliars
Input pulse width	t _{⊤IWH} , t _{TIWL}	TIOAn/TIOBn (when using as ECK, TIN)	-	2 t _{CYCP}	-	ns	



Trigger input timing

(V_{CC} = AV_{CC} = 2.7 V to 5.5 V, V_{SS} = AV_{SS} = 0 V, Ta = - 40°C to + 105°C)

Parameter	Symbol	Pin name	Conditions	Va	Value Unit Remarks		
Faranieter	Symbol	Finitialite	Conditions	Min	Max	Unit	Nenial NS
Input pulse width	ttrgh, ttrgl	TIOAn/TIOBn (when using as TGIN)	-	2 tcycp	-	ns	



Note:

t_{CYCP} indicates the APB bus clock cycle time.

For the number of the APB bus to which the Base Timer has been connected, see "8. Block Diagram".

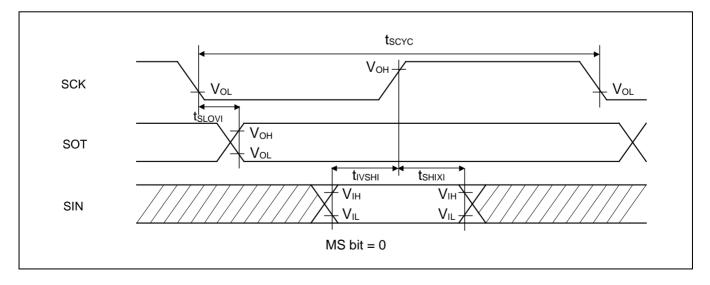


12.4.9 CSIO/UART Timing

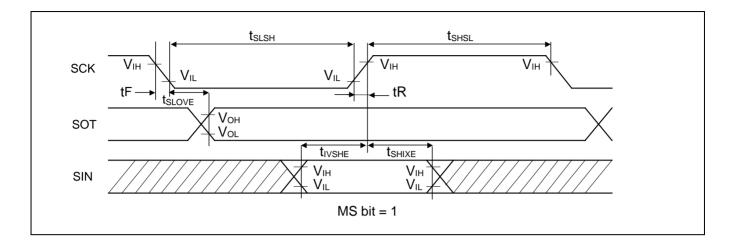
Synchronous serial (SPI = 0, SCINV = 0)

Demonstra	0. mate at	Pin		Vcc < 4	4.5 V	Vcc 2	4.5 V	11
Parameter	Symbol	name	Conditions	Min	Max	Min	Max	Unit
Baud rate	-	-	-	-	8	-	8	Mbps
Serial clock cycle time	tscyc	SCKx		4 t _{CYCP}	-	4 t _{CYCP}	-	ns
$SCK \downarrow \to SOT \text{ delay time}$	tslovi	SCKx, SOTx	Internal shift clock operation	- 30	+ 30	- 20	+ 20	ns
$SIN \to SCK \uparrow setup \ time$	t _{iVSHI}	SCKx, SINx		50	-	30	-	ns
$SCK \uparrow \to SIN \text{ hold time}$	tsнixi	SCKx, SINx		0	-	0	-	ns
Serial clock "L" pulse width	t _{SLSH}	SCKx		2 t _{СУСР} - 10	-	2 t _{CYCP} - 10	-	ns
Serial clock "H" pulse width	ts∺s∟	SCKx		tcycp + 10	-	tcycp + 10	-	ns
$SCK \downarrow \to SOT \text{ delay time}$	t SLOVE	SCKx, SOTx	External shift	-	50	-	30	ns
$SIN \to SCK \upharpoonright setup time$	tivshe	SCKx, SINx	clock operation	10	-	10	-	ns
$SCK \uparrow \to SIN \text{ hold time}$	tshixe	SCKx, SINx		20	-	20	-	ns
SCK falling time	tF	SCKx		-	5	-	5	ns
SCK rising time	tR	SCKx]	-	5	-	5	ns

- The above AC characteristics are for CLK synchronous mode.
- t_{CYCP} represents the APB bus clock cycle time.
- For the number of the APB bus to which Multi-function Serial has been connected, see "8. Block Diagram ". • The characteristics are only applicable when the relocate port numbers are the same.
- For instance, they are not applicable for the combination of SCKx_0 and SOTx_1.
- External load capacitance C_{L} = 30 pF







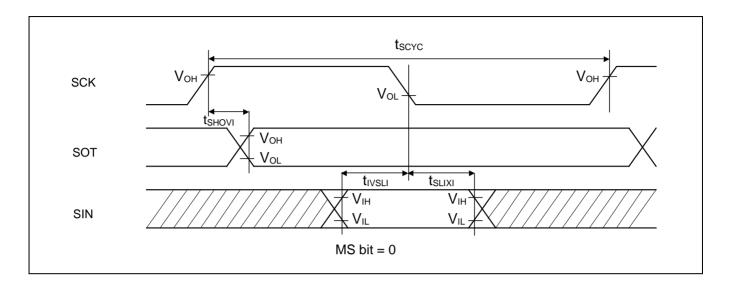
Synchronous serial (SPI = 0, SCINV = 1)

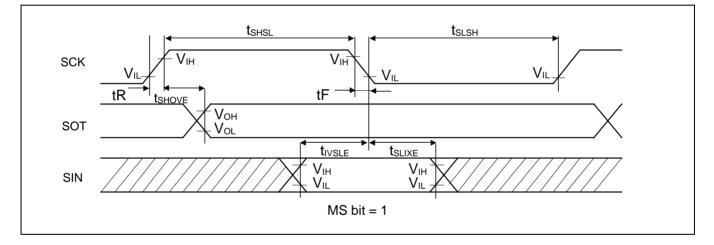
$(V_{CC} = AV_{CC} = 2.7 V \text{ to } 5.5 V, V_{SS} = AV_{SS} = 0$	V, Ta = -40° C to $+105^{\circ}$ C)
---	--

Parameter	Symbol	Pin	Conditions	V _{cc} <	4.5V	V _{cc} ≥	4.5V	Unit
Falalletei	Symbol	name	Conditions	Min	Max	Min	Max	Unit
Baud rate	-	-	-	-	8	-	8	Mbps
Serial clock cycle time	tscyc	SCKx		4 t _{CYCP}	-	4 t _{CYCP}	-	ns
$SCK \uparrow \to SOT \text{ delay time}$	tshovi	SCKx, SOTx	Internal shift	- 30	+ 30	- 20	+ 20	ns
$SIN \to SCK \downarrow setup time$	tı∨s∟ı	SCKx, SINx	clock operation	50	-	30	-	ns
$SCK \downarrow \to SIN \text{ hold time}$	t _{SLIXI}	SCKx, SINx		0	-	0	-	ns
Serial clock "L" pulse width	ts∟sн	SCKx		2 t _{CYCP} - 10	-	2 t _{CYCP} - 10	-	ns
Serial clock "H" pulse width	t SHSL	SCKx		tcycp + 10	-	tcycp + 10	-	ns
$SCK \uparrow \to SOT \text{ delay time}$	t SHOVE	SCKx, SOTx	External shift	-	50	-	30	ns
$\text{SIN} \rightarrow \text{SCK} \downarrow \text{setup time}$	tivsle	SCKx, SINx	clock operation	10	-	10	-	ns
$SCK \downarrow \to SIN \text{ hold time}$	tsLIXE	SCKx, SINx		20	-	20	-	ns
SCK falling time	tF	SCKx	1	-	5	-	5	ns
SCK rising time	tR	SCKx	1	-	5	-	5	ns

- The above AC characteristics are for CLK synchronous mode.
- tcycp represents the APB bus clock cycle time. For the number of the APB bus to which Multi-function Serial has been connected, see "8. Block Diagram ".
- The characteristics are only applicable when the relocate port numbers are the same. For instance, they are not applicable for the combination of SCKx_0 and SOTx_1.
- External load capacitance $C_L = 30 \text{ pF}$









Synchronous serial (SPI = 1, SCINV = 0)

Parameter	Symbol	Pin	Conditions	Vcc < 4	1.5 V	V _{cc} ≥ 4	4.5 V	Unit
Farameter	Symbol	name	Conditions	Min	Max	Min	Max	Unit
Baud rate	-	-	-	-	8	-	8	Mbps
Serial clock cycle time	tscyc	SCKx	Internal shift clock operation	4 tcycp	-	4 t _{CYCP}	-	ns
$SCK \uparrow \to SOT \text{ delay time}$	tsнovi	SCKx, SOTx		- 30	+ 30	- 20	+ 20	ns
$SIN \to SCK \downarrow setup \ time$	t _{IVSLI}	SCKx, SINx		50	-	30	-	ns
$SCK \downarrow \to SIN \text{ hold time}$	t _{SLIXI}	SCKx, SINx		0	-	0	-	ns
$\text{SOT} \rightarrow \text{SCK} \downarrow \text{delay time}$	t _{SOVLI}	SCKx, SOTx		2 t _{CYCP} - 30	-	2 t _{CYCP} - 30	-	ns
Serial clock "L" pulse width	ts∟sн	SCKx		2 t _{СҮСР} - 10	-	2 t _{СҮСР} - 10	-	ns
Serial clock "H" pulse width	tsнs∟	SCKx		tcycp + 10	-	tcycp + 10	-	ns
$SCK \uparrow \to SOT \text{ delay time}$	t _{SHOVE}	SCKx, SOTx	External shift	-	50	-	30	ns
$SIN \to SCK \downarrow setup \ time$	tivsle	SCKx, SINx	clock operation	10	-	10	-	ns
$SCK \downarrow \to SIN \text{ hold time}$	t _{SLIXE}	SCKx, SINx		20	-	20	-	ns
SCK falling time	tF	SCKx		-	5	-	5	ns
SCK rising time	tR	SCKx]	-	5	-	5	ns

Notes:

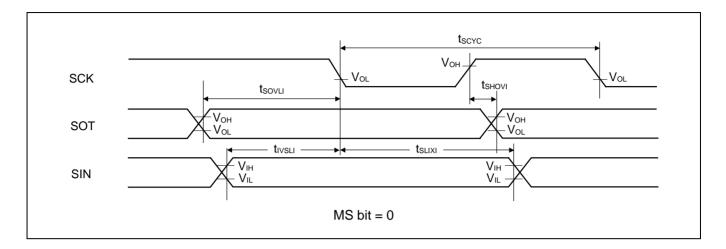
• The above AC characteristics are for CLK synchronous mode.

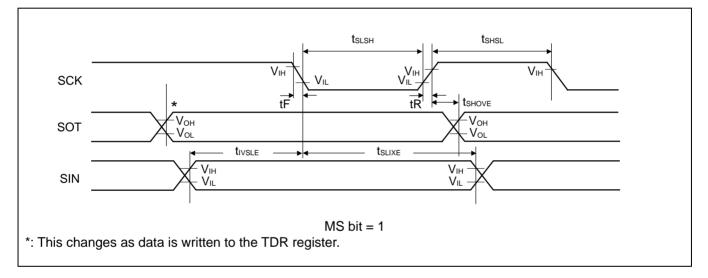
• tCYCP represents the APB bus clock cycle time. For the number of the APB bus to which Multi-function Serial has been connected, see "8. Block Diagram ".

• The characteristics are only applicable when the relocate port numbers are the same. For instance, they are not applicable for the combination of SCKx_0 and SOTx_1.

• External load capacitance C_L = 30 pF







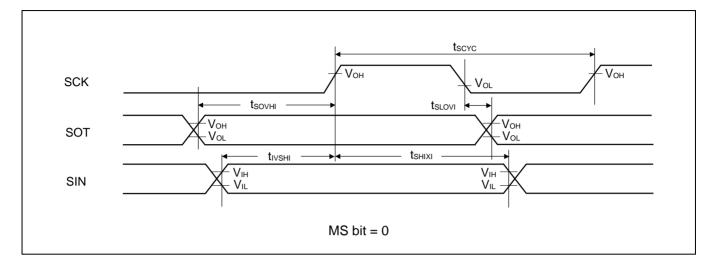


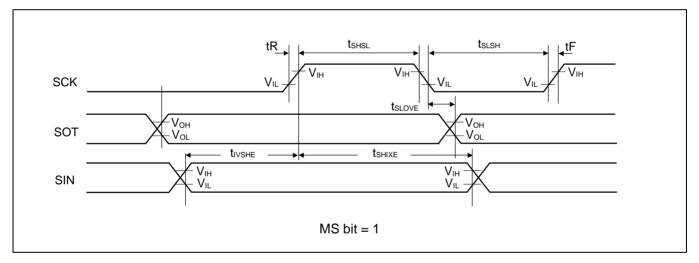
Synchronous serial (SPI = 1, SCINV = 1)

Parameter	O maked	Pin	Conditions	Vcc < 4	4.5 V	V _{cc} ≥ 4.5 V		11		
	Symbol	name		Min	Max	Min	Max	Unit		
Baud rate	-	-	-	-	8	-	8	Mbps		
Serial clock cycle time	tscyc	SCKx		4 t _{CYCP}	-	4 t _{CYCP}	-	ns		
SCK $\downarrow \rightarrow$ SOT delay time	tslovi	SCKx, SOTx	 Internal shift clock operation 			- 30	+ 30	- 20	+ 20	ns
$SIN \to SCK \upharpoonright setup time$	t _{i∨sнi}	SCKx, SINx		50	-	30	-	ns		
$SCK \uparrow \to SIN \text{ hold time}$	tshixi	SCKx, SINx		0	-	0	-	ns		
$SOT \to SCK \uparrow delay \ time$	tsovнi	SCKx, SOTx		2 t _{CYCP} - 30	-	2 t _{CYCP} - 30	-	ns		
Serial clock "L" pulse width	tslsh	SCKx		2 t _{CYCP} - 10	-	2 t _{CYCP} - 10	-	ns		
Serial clock "H" pulse width	ts∺s∟	SCKx		tcycp + 10	-	tcycp + 10	-	ns		
$SCK \downarrow \to SOT$ delay time	t SLOVE	SCKx, SOTx	External shift	-	50	-	30	ns		
$SIN \to SCK \uparrow setup \ time$	tivshe	SCKx, SINx	clock operation	10	-	10	-	ns		
$SCK \uparrow \to SIN \text{ hold time}$	tshixe	SCKx, SINx		20	-	20	-	ns		
SCK falling time	tF	SCKx		-	5	-	5	ns		
SCK rising time	tR	SCKx	1	-	5	-	5	ns		

- The above AC characteristics are for CLK synchronous mode.
- t_{CYCP} represents the APB bus clock cycle time.
- For the number of the APB bus to which Multi-function Serial has been connected, see "8. Block Diagram ".
- The characteristics are only applicable when the relocate port numbers are the same. For instance, they are not applicable for the combination of SCKx_0 and SOTx_1.
- External load capacitance $C_L = 30 \text{ pF}$









When using synchronous serial chip select (SCINV = 0, CSLVL=1)

 $(V_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = 0V)$

Parameter	Symbol	Conditions	V _{cc} <	4.5V	V _{cc} ≥	Unit	
	Symbol	Conditions	Min	Max	Min	Max	Onit
SCS↓→SCK↓ setup time	t _{CSSI}	laterael ekift	(*1)-50	(*1)+0	(*1)-50	(*1)+0	ns
SCK↑→SCS↑ hold time	tсsні	Internal shift clock operation	(*2)+0	(*2)+50	(*2)+0	(*2)+50	ns
SCS deselect time	tcsDI		(*3)-50 +5tcycp	(*3)+50 +5t _{CYCP}	(*3)-50 +5tcycp	(*3)+50 +5tcycp	ns
SCS↓→SCK↓ setup time	tcsse		3tcycp+30	-	3tcycp+30	-	ns
SCK↑→SCS↑ hold time	t CSHE	External shift	0	-	0	-	ns
SCS deselect time	t _{CSDE}	clock	3t _{CYCP} +30	-	3t _{CYCP} +30	-	ns
SCS↓→SUT delay time	t _{DSE}	operation	-	40	-	40	ns
SCS↑→SUT delay time	t DEE		0	-	0	-	ns

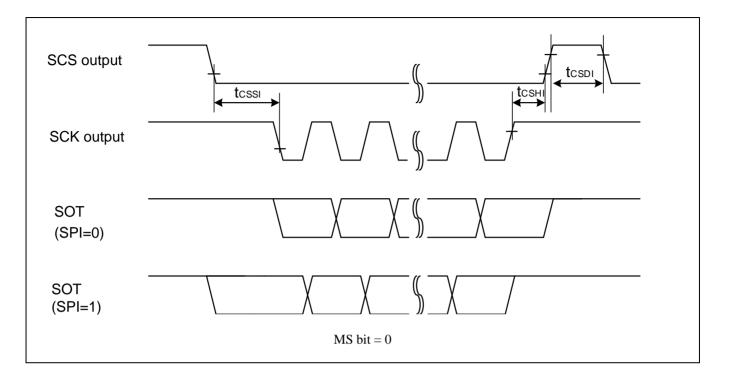
(*1): CSSU bit value × serial chip select timing operating clock cycle [ns]

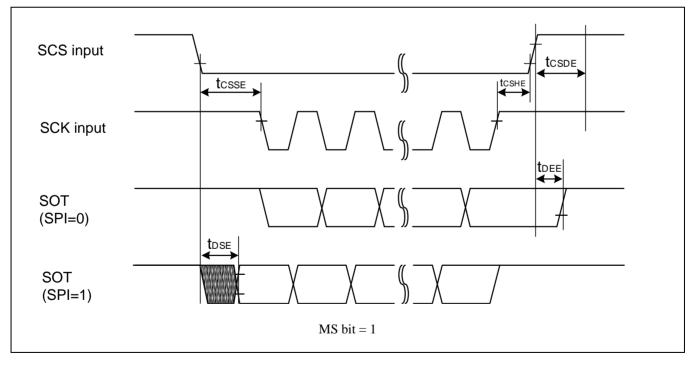
(*2): CSHD bit value × serial chip select timing operating clock cycle [ns]

(*3): CSDS bit value x serial chip select timing operating clock cycle [ns]

- t_{CYCP} indicates the APB bus clock cycle time.
 About the APB bus number which Multi-function Serial is connected to, see "8. Block Diagram ".
- About CSSU, CSHD, CSDS, serial chip select timing operating clock, see "FM0+ Family PERIPHERAL MANUAL".
- The characteristics are only applicable when the relocate port numbers are the same. For instance, they are not applicable for the combination of SCKx_0 and SCSx0_1.
- When the external load capacitance $C_L = 30 pF$.









When using synchronous serial chip select (SCINV = 1, CSLVL=1)

 $(V_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = 0V)$

					-		
Parameter	Symbol	Conditions	Vcc <	4.5V	V _{cc} ≥	Unit	
	Symbol	Conditions	Min	Max	Min	Max	
SCS↓→SCK↑ setup time	tcssi	Internal chift	(*1)-50	(*1)+0	(*1)-50	(*1)+0	ns
SCK↓→SCS↑ hold time	tcsнi	Internal shift clock operation	(*2)+0	(*2)+50	(*2)+0	(*2)+50	ns
SCS deselect time	tcsDI		(*3)-50 +5t _{CYCP}	(*3)+50 +5t _{CYCP}	(*3)-50 +5tcycp	(*3)+50 +5t _{CYCP}	ns
$SCS \downarrow \rightarrow SCK \uparrow$ setup time	tcsse		3tcycp+30	-	3tcycp+30	-	ns
SCK↓→SCS↑ hold time	t _{CSHE}	External shift	0	-	0	-	ns
SCS deselect time	tcsde	clock	3tcycp+30	-	3tcycp+30	-	ns
$SCS\downarrow \rightarrow SOT$ delay time	tDSE	operation	-	40	-	40	ns
$SCS\uparrow \rightarrow SOT$ delay time	t _{DEE}		0	-	0	-	ns

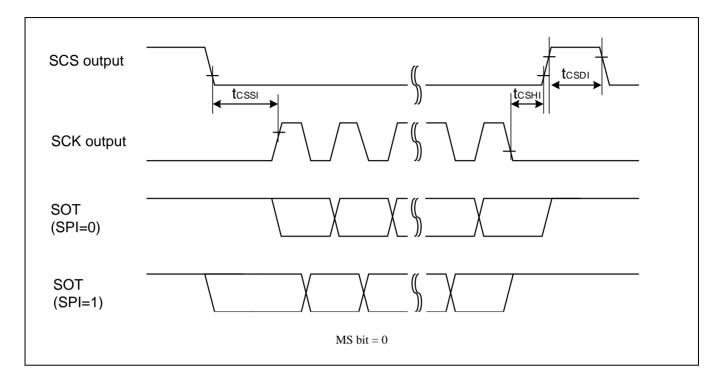
(*1): CSSU bit value × serial chip select timing operating clock cycle [ns]

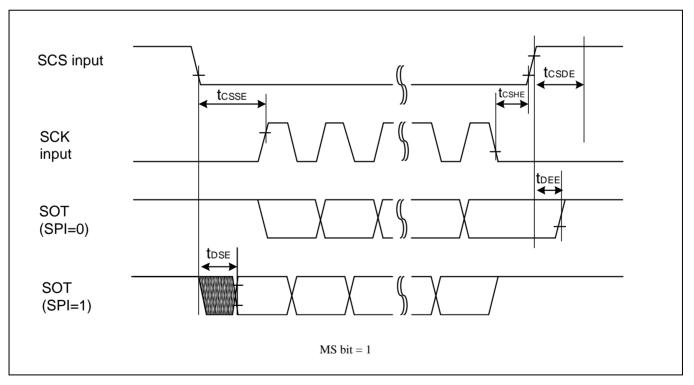
(*2): CSHD bit value x serial chip select timing operating clock cycle [ns]

(*3): CSDS bit value × serial chip select timing operating clock cycle [ns]

- t_{CYCP} indicates the APB bus clock cycle time.
- About the APB bus number which Multi-function Serial is connected to, see "8. Block Diagram ".
- About CSSU, CSHD, CSDS, serial chip select timing operating clock, see "FM0+ Family PERIPHERAL MANUAL".
- The characteristics are only applicable when the relocate port numbers are the same.
- For instance, they are not applicable for the combination of SCKx_0 and SCSx0_1.
- When the external load capacitance $C_L = 30 pF$.









When using synchronous serial chip select (SCINV = 0, CSLVL=0)

$(V_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = 0V)$

Parameter	Symbol	Conditions	Vcc <	Vcc < 4.5V		4.5V	Unit
	Symbol	Conditions	Min	Max	Min	Max	Onit
SCS↑→SCK↓ setup time	tcssi	Internal shift	(*1)-50	(*1)+0	(*1)-50	(*1)+0	ns
SCK↑→SCS↓ hold time	tсsні	clock operation	(*2)+0	(*2)+50	(*2)+0	(*2)+50	ns
SCS deselect time	tcsDI		(*3)-50 +5tcycp	(*3)+50 +5tcycp	(*3)-50 +5tcycp	(*3)+50 +5tcycp	ns
SCS↑→SCK↓ setup time	tcsse		3tcycp+30	-	3tcycp+30	-	ns
SCK↑→SCS↓ hold time	t _{CSHE}	External shift	0	-	0	-	ns
SCS deselect time	t CSDE	clock	3tcycp+30	-	3tcycp+30	-	ns
SCS↑→SOT delay time	tDSE	operation	-	40	-	40	ns
SCS↓→SOT delay time	t _{DEE}		0	-	0	-	ns

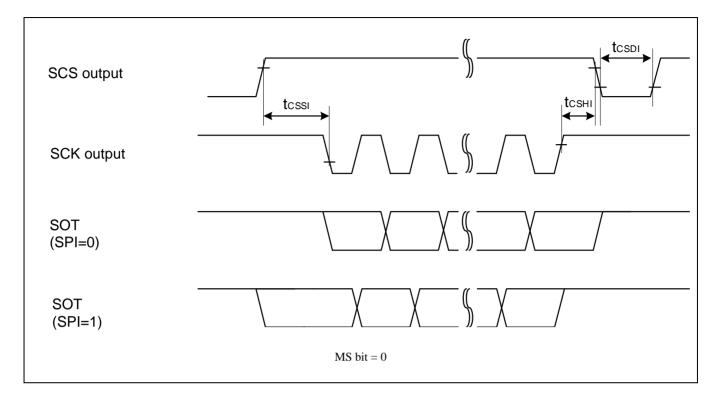
(*1): CSSU bit value × serial chip select timing operating clock cycle [ns]

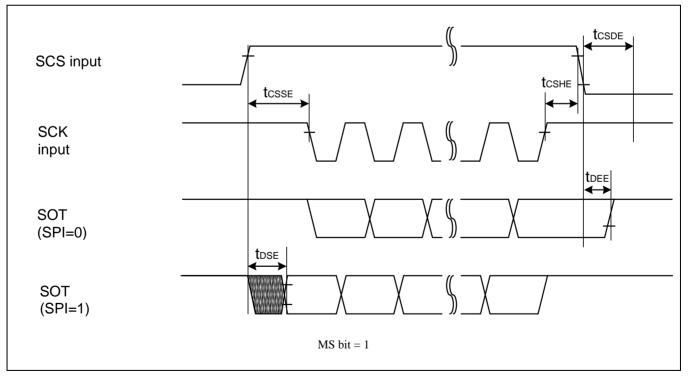
(*2): CSHD bit value × serial chip select timing operating clock cycle [ns]

(*3): CSDS bit value x serial chip select timing operating clock cycle [ns]

- t_{CYCP} indicates the APB bus clock cycle time.
- About the APB bus number which Multi-function Serial is connected to, see "8. Block Diagram ".
- About CSSU, CSHD, CSDS, serial chip select timing operating clock, see "FM0+ Family PERIPHERAL MANUAL".
- The characteristics are only applicable when the relocate port numbers are the same.
- For instance, they are not applicable for the combination of SCKx_0 and SCSx0_1.
- When the external load capacitance $C_L = 30 pF$.









When using synchronous serial chip select (SCINV = 1, CSLVL=0)

$(V_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = 0V)$

Parameter	Symbol	Conditions	Vcc < 4.5V		V _{CC} ≥ 4.5V		Unit	
	Symbol	Conditions	Min	Max	Min	Мах		
SCS↑→SCK↑ setup time	tcssi	Internal shift	(*1)-50	(*1)+0	(*1)-50	(*1)+0	ns	
$SCK\downarrow \rightarrow SCS\downarrow$ hold time	tсsні	clock operation	(*2)+0	(*2)+50	(*2)+0	(*2)+50	ns	
SCS deselect time	tcsDI		(*3)-50 +5tcycp	(*3)+50 +5tcycp	(*3)-50 +5tcycp	(*3)+50 +5t _{CYCP}	ns	
SCS↑→SCK↑ setup time	tcsse		3tcycp+30	-	3tcycp+30	-	ns	
$SCK\downarrow \rightarrow SCS\downarrow$ hold time	t _{CSHE}	External shift	0	-	0	-	ns	
SCS deselect time	tcsde	clock	3tcycp+30	-	3tcycp+30	-	ns	
SCS↑→SOT delay time	tDSE	operation	-	40	-	40	ns	
SCS↓→SOT delay time	t _{DEE}		0	-	0	-	ns	

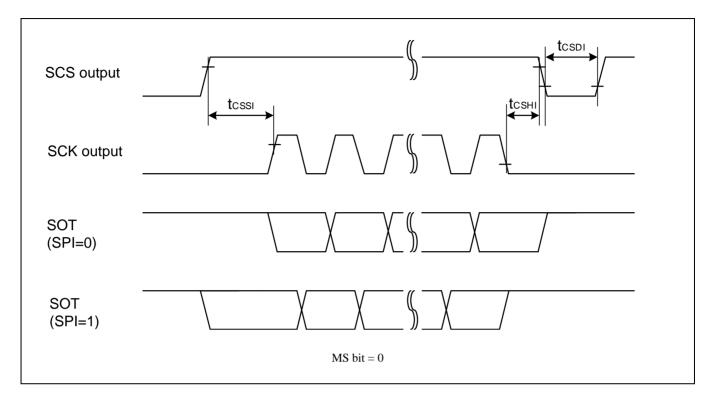
(*1): CSSU bit value × serial chip select timing operating clock cycle [ns]

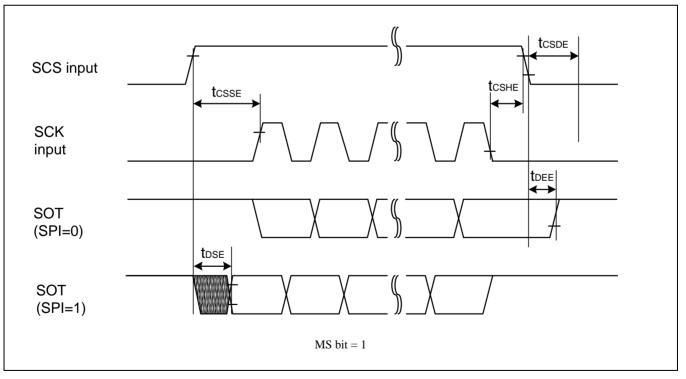
(*2): CSHD bit value x serial chip select timing operating clock cycle [ns]

(*3): CSDS bit value x serial chip select timing operating clock cycle [ns]

- t_{CYCP} indicates the APB bus clock cycle time.
- About the APB bus number which Multi-function Serial is connected to, see "8. Block Diagram ".
- About CSSU, CSHD, CSDS, serial chip select timing operating clock, see "FM0+ Family PERIPHERAL MANUAL".
- The characteristics are only applicable when the relocate port numbers are the same.
- For instance, they are not applicable for the combination of SCKx_0 and SCSx0_1.
- When the external load capacitance $C_L = 30 pF$.





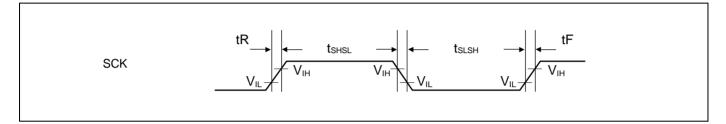




External clock (EXT = 1): asynchronous only

$(V_{CC} = AV_{CC} = 2.7)$	7 V to 5.5 V, Vss = AVss =	$= 0 V$, Ta $= -40^{\circ}C to + 105^{\circ}C$)
----------------------------	----------------------------	---

Parameter	Symbol	Conditions		Unit	Remarks	
			Min	Max	Onit	itemarks
Serial clock "L" pulse width	ts∟sн	C∟ = 30 pF	tcycp + 10	-	ns	
Serial clock "H" pulse width	ts∺s∟		tcycp + 10	-	ns	
SCK falling time	tF		-	5	ns	
SCK rising time	tR		-	5	ns	



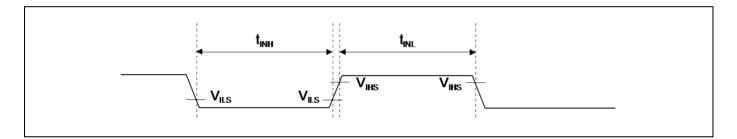


12.4.10 External Input Timing

	Jac mining		(Vcc = AVc	cc = 2.7 V to 5.5 V,	Vss = AV	/ss = 0 V,	Ta = - 40°C to + 105				
Parameter	Symbol	Pin name	Conditions	Value Min Max		Value Min Max				Unit	Remarks
		ADTGx	-			ns	A/D converter trigger input				
		FRCKx		2 t _{CYCP} *1	-		Free-run timer input clock				
Input pulse width	tinh, tinl	ICxx					Input capture				
		DTTIxX	-	2 t _{CYCP} *1	-	ns	Wave form generator				
	INTxx, NMIX		2 t _{CYCP} + 100*1	-	ns	External					
			-	500* ²	-	ns	interrupt, NMI				

*1: t_{CYCP} represents the APB bus clock cycle time except when the APB bus clock stops in STOP mode or in TIMER mode. For the number of the APB bus to which the Multi-function Timer is connected and that of the APB bus to which the External Interrupt Controller is connected, see "8. Block Diagram".

*2: In STOP mode and TIMER mode



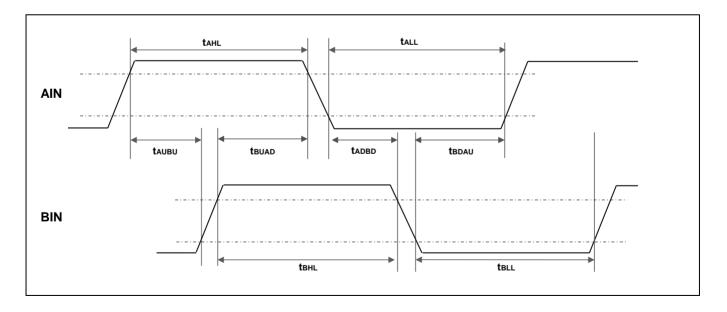


12.4.11 QPRC Timing

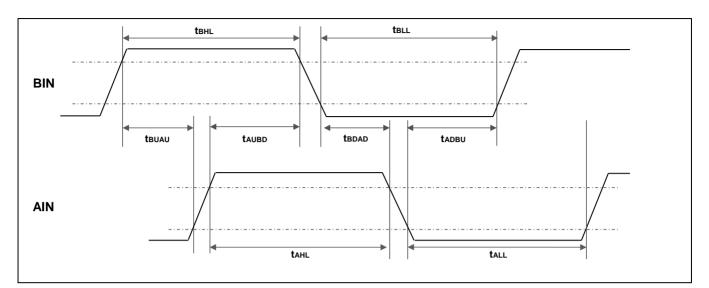
(Vcc = AVcc = 2.7 V to 5.5 V, Vss = AVss = 0 V, Ta = - 40°C to + 105°C)

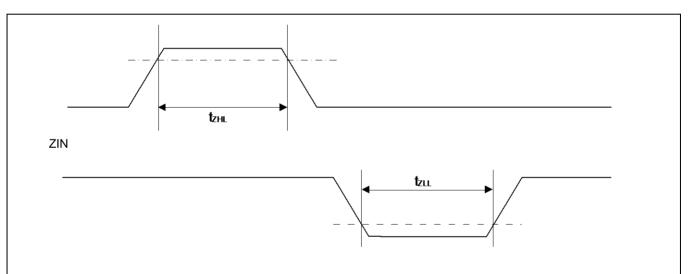
Parameter	Symbol	Conditions	V	alue	Unit
Falallelel	Symbol	Conditions	Min	Max	Unit
AIN pin "H" width	t _{AHL}	-			
AIN pin "L" width	tALL	-			
BIN pin "H" width	t _{BHL}	-			
BIN pin "L" width	t _{BLL}	-			
Time from AIN pin "H" level to BIN rise	taubu	PC_Mode2 or PC_Mode3			
Time from BIN pin "H" level to AIN fall	t _{BUAD}	PC_Mode2 or PC_Mode3			
Time from AIN pin "L" level to BIN fall	tadbd	PC_Mode2 or PC_Mode3			
Time from BIN pin "L" level to AIN rise	t _{BDAU}	PC_Mode2 or PC_Mode3			
Time from BIN pin "H" level to AIN rise	tbuau	PC_Mode2 or PC_Mode3	2 t _{CYCP} *	-	ns
Time from AIN pin "H" level to BIN fall	t _{AUBD}	PC_Mode2 or PC_Mode3			
Time from BIN pin "L" level to AIN fall	t BDAD	PC_Mode2 or PC_Mode3			
Time from AIN pin "L" level to BIN rise	t adbu	PC_Mode2 or PC_Mode3			
ZIN pin "H" width	t _{ZHL}	QCR:CGSC="0"			
ZIN pin "L" width	t _{ZLL}	QCR:CGSC="0"			
Time from determined ZIN level to AIN/BIN rise and fall	t _{ZABE}	QCR:CGSC="1"			
Time from AIN/BIN rise and fall time to determined ZIN level	tabez	QCR:CGSC="1"			

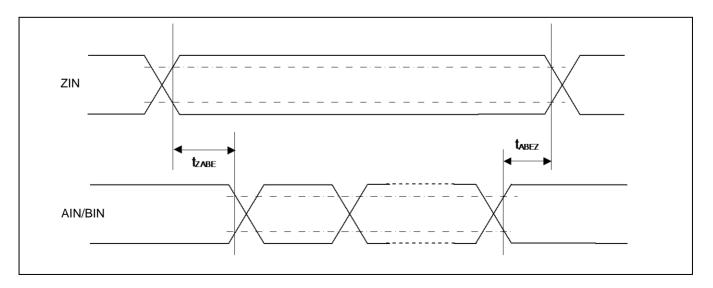
*: tcycP represents the APB bus clock cycle time except when the APB bus clock stops in STOP mode or in TIMER mode. For the number of the APB bus to which the QPRC is connected, see "8. Block Diagram".













12.4.12 PC Timing

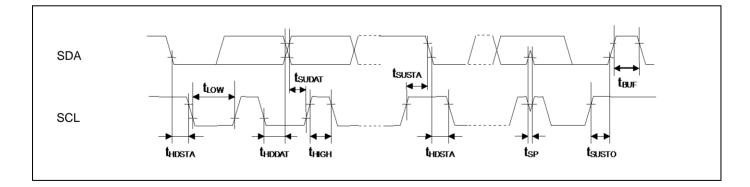
_			Standar	d-mode	Fast-r	node		
Parameter	Symbol	Conditions	Min	Max	Min	Max	Unit	Remarks
SCL clock frequency	FSCL		0	100	0	400	kHz	
(Repeated) START condition hold time SDA $\downarrow \rightarrow$ SCL \downarrow	t hdsta		4.0	-	0.6	-	μs	
SCL clock "L" width	tLOW		4.7	-	1.3	-	μs	
SCL clock "H" width	tніgн		4.0	-	0.6	-	μs	
(Repeated) START setup time SCL $\uparrow \rightarrow$ SDA \downarrow	t susta	C∟ = 30 pF,	4.7	-	0.6	-	μs	
Data hold time $SCL \downarrow \rightarrow SDA \downarrow \uparrow$	t _{HDDAT}	$R = (Vp/I_{OL})^{*1}$	0	3.45* ²	0	0.9* ³	μs	
Data setup time SDA $\downarrow \uparrow \rightarrow$ SCL \uparrow	t SUDAT		250	-	100	-	ns	
STOP condition setup time SCL $\uparrow \rightarrow$ SDA \uparrow	tsusтo		4.0	-	0.6	-	μs	
Bus free time between "STOP condition" and "START condition"	tbuf		4.7	-	1.3	-	μs	
Noise filter	tsp	-	2 tcycp*4	-	2 tcycp*4	-	ns	

*1: R represents the pull-up resistance of the SCL and SDA lines, and CL the load capacitance of the SCL and SDA lines. Vp represents the power supply voltage of the pull-up resistance, and IoL the VoL guaranteed current.

*2: The maximum t_{HDDAT} must satisfy at least the condition that the period during which the device is holding the SCL signal at "L" (t_{LOW}) does not extend.

*3: A Fast-mode I²C bus device can be used in a Standard-mode I²C bus system, provided that the condition of "t_{SUDAT} ≥ 250 ns" is fulfilled.

*4: t_{CYCP} represents the APB bus clock cycle time.
 For the number of the APB bus to which the I²C is connected, see "8. Block Diagram".
 To use Standard-mode, set the APB bus clock at 2MHz or more.
 To use Fast-mode, set the APB bus clock at 8 MHz or more.





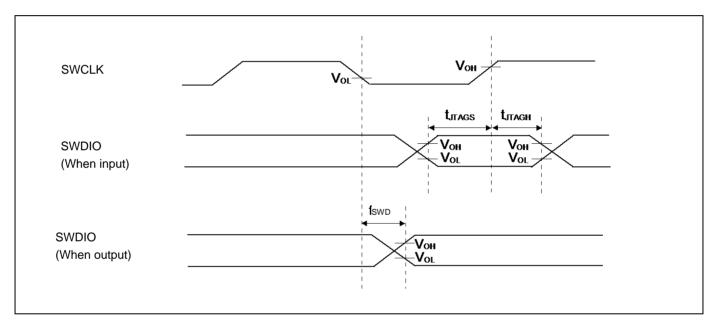
12.4.13 SW-DP Timing

(Vcc = AVcc = 2.7 V to 5.5 V, Vss = AVss = 0 V, Ta = - 40°C to + 105°C)

Parameter	Symbol	Pin name	Conditions	Va	lue	Unit	Remarks
Farameter	Symbol	Min Max	Max	Unit	Reillarks		
SWDIO setup time	tsws	SWCLK, SWDIO	-	15	-	ns	
SWDIO hold time	t _{swн}	SWCLK, SWDIO	-	15	-	ns	
SWDIO delay time	tswD	SWCLK, SWDIO	-	-	45	ns	

Note:

• External load capacitance $C_L = 30 \text{ pF}$





12.5 12-bit A/D Converter

Electrical characteristics of A/D Converter

Parameter	Symbol	Pin name	Value			Unit	Remarks
Falalletei	Symbol	Fill liallie	Min	Тур	Max	Unit	Relliarks
Resolution	-	-	-	-	12	bit	
Integral Nonlinearity	-	-	- 4.5	-	4.5	LSB	
Differential Nonlinearity	-	-	- 2.5	-	+ 2.5	LSB	
Zero transition voltage	Vzt	ANxx	- 20	-	+ 20	mV	
Full cools transition voltage	V _{FST}	ANxx	AVRH - 20	-	AVRH+ 20	mV	S6E1A1xC0A
Full-scale transition voltage	VFST	AINXX	AVcc-20	-	AVcc+20		S6E1A1xB0A
			0.8*1				S6E1A1xC0A
Conversion time	-	-	0.0	-	-	μs	$AV_{CC} \ge 4.5V$
			2.0*1	-	-		S6E1A1xB0A
			0.04				S6E1A1xC0A
Sampling time*2		-	0.24		10		$AV_{CC} \ge 4.5V$
	Ts		-	-		μs	S6E1A1xC0A
			0.3				$AV_{CC} < 4.5V$
			0.6				S6E1A1xB0A
	Tcck	-	40				S6E1A1xC0A
			40				$AV_{CC} \ge 4.5V$
Compare clock cycle*3			50	-	1000	ns	S6E1A1xC0A
			50				$AV_{CC} < 4.5V$
			100				S6E1A1xB0A
State transition time to	Tstt	_		-	1.0		
operation permission	ISU	-	-	-	1.0	μs	
Analog input capacity	CAIN	-	-	-	9.7	pF	
A I · · · · ·	5				1.6		$AV_{CC} \ge 4.5V$
Analog input resistance	RAIN	-	-	-	2.3	kΩ	AVcc < 4.5V
Interchannel disparity	-	-	-	-	4	LSB	
Analog port input current	-	ANxx	-	-	5	μΑ	
v			AVss	-	AVRH	V	S6E1A1xC0A
Analog input voltage	-	ANxx	AVss	-	AVcc	v	S6E1A1xB0A
Reference voltage	-	AVRH	2.7	-	AVcc	V	Only S6E1A1xB0A

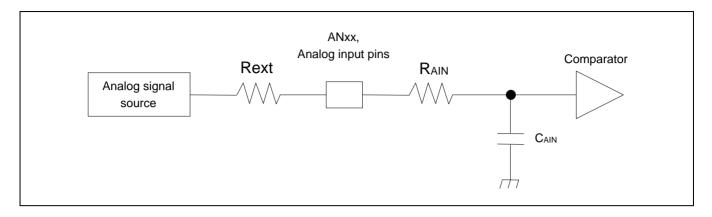
*1: The conversion time is the value of "sampling time (Ts) + compare time (Tc)". The minimum conversion time is computed according to the following conditions: sampling time = 240 ns, compare time = 560 ns (AVcc ≥ 4.5 V). Must be set 25MHz to the Base clock (HCLK). Ensure that the conversion time satisfies the specifications of the sampling time (Ts) and compare clock cycle (Tcck).

For details of the settings of the sampling time and compare clock cycle, refer to "CHAPTER: A/D Converter" in "FM0+ Family PERIPHERAL MANUAL Analog Macro Part".

The register settings of the A/D Converter are reflected in the operation according to the APB bus clock timing. For the number of the APB bus to which the A/D Converter is connected, see "8. Block Diagram". The base clock (HCLK) is used to generate the sampling time and the compare clock cycle.

- *2: The required sampling time varies according to the external impedance. Set a sampling time that satisfies (Equation 1).
- *3: The compare time (Tc) is the result of (Equation 2).





(Equation 1) Ts \geq (R_{AIN} + Rext) × C_{AIN} × 9

Ts:	Sampling time
RAIN:	Input resistance of A/D Converter = 1.6 k Ω with 4.5 < AVCC < 5.5 ch.1 to ch.5
	Input resistance of A/D Converter = 1.4 k Ω with 4.5 < AVCC < 5.5 ch.0, ch.6, ch.7
	Input resistance of A/D Converter = 2.3 k Ω with 2.7 < AVCC < 4.5 ch.1 to ch.5
	Input resistance of A/D Converter = 2.0 k Ω with 2.7 < AVCC < 4.5 ch.0, ch.6, ch.7
CAIN:	Input capacitance of A/D Converter = 9.7 pF with 2.7 < AVCC < 5.5
Rext:	Output impedance of external circuit

(Equation 2) Tc = Tcck \times 14

Tc:	Compare time
Tcck:	Compare clock cycle



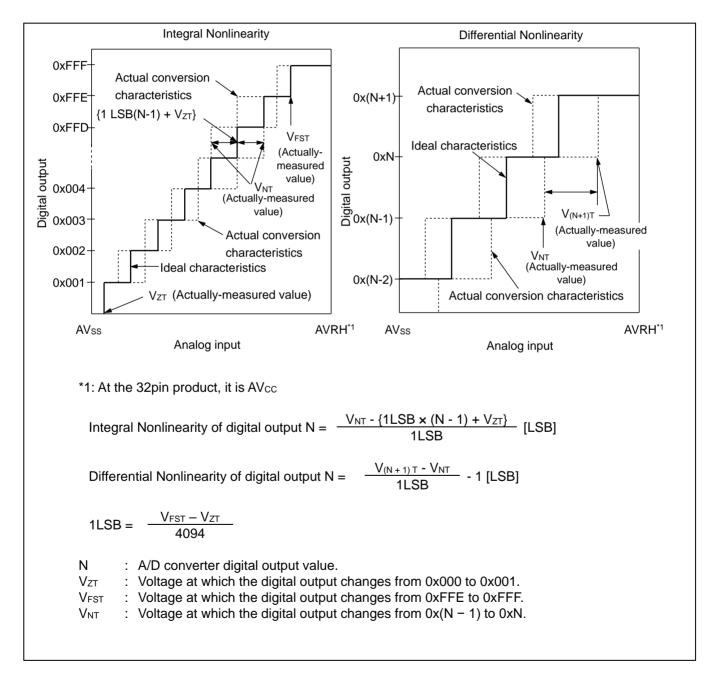
Definitions of 12-bit A/D Converter terms

- Resolution
- : Analog variation that is recognized by an A/D converter.
- Integral Nonlinearity

: Deviation of the line between the zero-transition point (0b00000000000 $\leftarrow \rightarrow$

- (b) (b)
- Differential Nonlinearity

: Deviation from the ideal value of the input voltage that is required to change the output code by 1 LSB.







12.6 Low-voltage Detection Characteristics

12.6.1 Low-voltage Detection Reset

 $(Ta = -40^{\circ}C to + 105^{\circ}C)$

Parameter	Symbol	Conditions		Value		Unit	Remarks
Parameter	Symbol	Conditions	Min	Тур	Max	Unit	Remarks
Detected voltage	VDL	SVHR ^{*1} =	2.25	2.45	2.65	V	When voltage drops
Released voltage	VDH	00000	2.30	2.50	2.70	V	When voltage rises
Detected voltage	VDL	SVHR ^{*1} =	2.39	2.60	2.81	V	When voltage drops
Released voltage	VDH	00001	Same as S	VHR = 0000	0 value	V	When voltage rises
Detected voltage	VDL	SVHR ^{*1} =	2.48	2.70	2.92	V	When voltage drops
Released voltage	VDH	00010	Same as S	VHR = 0000	0 value	V	When voltage rises
Detected voltage	VDL	SVHR ^{*1} =	2.58	2.80	3.02	V	When voltage drops
Released voltage	VDH	00011	Same as S	VHR = 0000	0 value	V	When voltage rises
Detected voltage	VDL	SVHR ^{*1} =	2.76	3.00	3.24	V	When voltage drops
Released voltage	VDH	00100	Same as S	VHR = 0000	0 value	V	When voltage rises
Detected voltage	VDL	SVHR ^{*1} =	2.94	3.20	3.46	V	When voltage drops
Released voltage	VDH	00101	Same as S	VHR = 0000	0 value	V	When voltage rises
Detected voltage	VDL	SVHR ^{*1} =	3.31	3.60	3.89	V	When voltage drops
Released voltage	VDH	00110	Same as S	VHR = 0000	0 value	V	When voltage rises
Detected voltage	VDL	SVHR ^{*1} =	3.40	3.70	4.00	V	When voltage drops
Released voltage	VDH	00111	Same as S	VHR = 0000	0 value	V	When voltage rises
Detected voltage	VDL	SVHR ^{*1} =	3.68	4.00	4.32	V	When voltage drops
Released voltage	VDH	01000	Same as S	VHR = 0000	0 value	V	When voltage rises
Detected voltage	VDL	SVHR ^{*1} =	3.77	4.10	4.43	V	When voltage drops
Released voltage	VDH	01001	Same as S	VHR = 0000	0 value	V	When voltage rises
Detected voltage	VDL	SVHR ^{*1} =	3.86	4.20	4.54	V	When voltage drops
Released voltage	VDH	01010	Same as S	VHR = 0000	0 value	V	When voltage rises
LVD stabilization wait time	T _{LVDW}	-	-	-	8160× t _{CYCP} *2	μs	
LVD detection delay time	Tlvddl	-	-	-	200	μs	

*1: SVHR bit of Low-Voltage Detection Voltage Control Register (LVD_CTL) is reset to SVHR = 00000 by low voltage detection reset.

*2: t_{CYCP} indicates the APB1 bus clock cycle time.



12.6.2 Low-voltage Detection Interrupt

 $(Ta = -40^{\circ}C to + 105^{\circ}C)$

Parameter	Symbol	Conditions		Value		Uni	Remarks
Farameter	Symbol	Conditions	Min	Тур	Max	t	itemarks
Detected voltage	VDL	SVHI = 00011	2.58	2.80	3.02	V	When voltage drops
Released voltage	VDH	3011 = 00011	2.67	2.90	3.13	V	When voltage rises
Detected voltage	VDL	SVHI = 00100	2.76	3.00	3.24	V	When voltage drops
Released voltage	VDH	SVHI = 00100	2.85	3.10	3.35	V	When voltage rises
Detected voltage	VDL	SVHI = 00101	2.94	3.20	3.46	V	When voltage drops
Released voltage	VDH	SVHI = 00101	3.04	3.30	3.56	V	When voltage rises
Detected voltage	VDL	SVHI = 00110	3.31	3.60	3.89	V	When voltage drops
Released voltage	VDH	3011 = 00110	3.40	3.70	4.00	V	When voltage rises
Detected voltage	VDL	SVHI = 00111	3.40	3.70	4.00	V	When voltage drops
Released voltage	VDH	3011 = 00111	3.50	3.80	4.10	V	When voltage rises
Detected voltage	VDL	SVHI = 01000	3.68	4.00	4.32	V	When voltage drops
Released voltage	VDH	3011 = 01000	3.77	4.10	4.43	V	When voltage rises
Detected voltage	VDL	SVHI = 01001	3.77	4.10	4.43	V	When voltage drops
Released voltage	VDH	30111 = 01001	3.86	4.20	4.54	V	When voltage rises
Detected voltage	VDL	SVHI = 01010	3.86	4.20	4.54	V	When voltage drops
Released voltage	VDH	3011 = 01010	3.96	4.30	4.64	V	When voltage rises
LVD stabilization wait time	T _{LVDW}	-	-	-	8160 × t _{CYCP} *	μs	
LVD detection delay time	TLVDDL	-	-	-	200	μs	

*:t_{CYCP} represents the APB1 bus clock cycle time.



12.7 Flash Memory Write/Erase Characteristics

 $(V_{CC} = 2.7 \text{ V to } 5.5 \text{ V}, \text{ Ta} = -40^{\circ}\text{C to} + 105^{\circ}\text{C})$

Paramete	r		Value		Unit	Remarks
Faramete		Min	Тур	Max	Unit	Kellidi K5
Sector erase time	Large sector	-	0.7	2.2		The sector erase time includes the time of
Sector erase time	Small sector		0.3	0.9	s	writing prior to internal erase.
Halfword (16-bit) write	time	-	30	528	μs	The halfword (16-bit) write time excludes the system-level overhead.
Chip erase time		-	2.6	8	s	The chip erase time includes the time of writing prior to internal erase.

Write/erase cycle and data hold time

Write/erase cycle	Data hold time (year)	Remarks
1,000	20*	
10,000	10*	

*: This value was converted from the result of a technology reliability assessment. (This value was converted from the result of a high temperature accelerated test using the Arrhenius equation with the average temperature value being + 85°C).



12.8 Return Time from Low-Power Consumption Mode

12.8.1 Return Factor: Interrupt

The return time from Low-Power consumption mode is indicated as follows. It is from receiving the return factor to starting the program operation.

Return Count Time

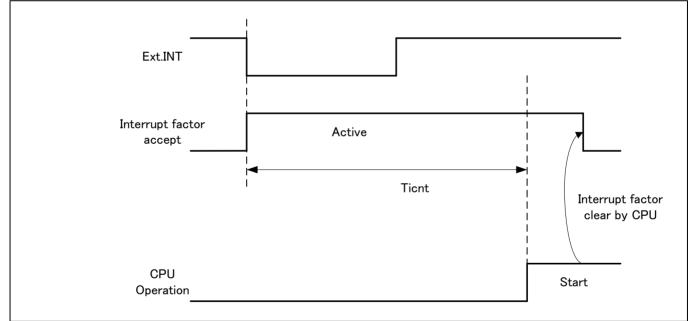
(V_{CC} = 2.7V to 5.5V, Ta = - 40°C to + 105°C)

Parameter	Symbol	Va	alue*	Unit	Remarks
Falailletei	Symbol	Тур	Max	Unit	Remarks
SLEEP mode		tcycc		μs	
High-speed CR TIMER mode, Main TIMER mode, PLL TIMER mode		40 + 17 × tcycc	80 + 17 × t _{CYCC}	μs	
Low-speed CR TIMER mode	Ticnt	360	720	μs	
Sub TIMER mode]	191	381	μs	
RTC mode, STOP mode		819	1090	μs	

*: The value depends on the accuracy of built-in CR.

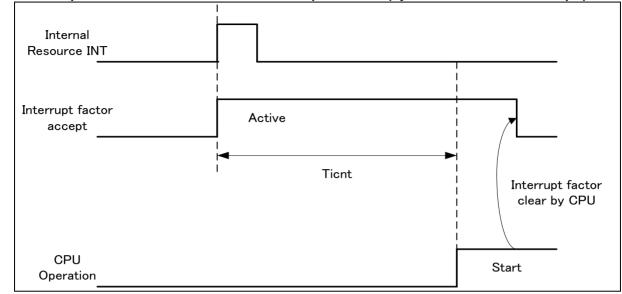
The stabilization time of Main clock/Sub clock/Main PLL clock is not included.

Operation example of return from Low-Power consumption mode (by external interrupt*)



*: External interrupt is set to detecting fall edge.





Operation example of return from Low-Power consumption mode (by internal resource interrupt*)

*: Internal resource interrupt is not included in return factor by the kind of Low-Power consumption mode.

Notes:

- The return factor is different in each Low-Power consumption modes.
- See "Chapter: Low Power Consumption Mode" and "Operations of Standby Modes" in FM0+ Family PERIPHERAL MANUAL.
 When interrupt recoveries, the operation mode that CPU recoveries depends on the state before the Low-Power consumption mode transition. See "CHAPTER: Low Power Consumption Mode" in "FM0+ Family PERIPHERAL MANUAL".



12.8.2 Return Factor: Reset

The return time from Low-Power consumption mode is indicated as follows. It is from releasing reset to starting the program operation.

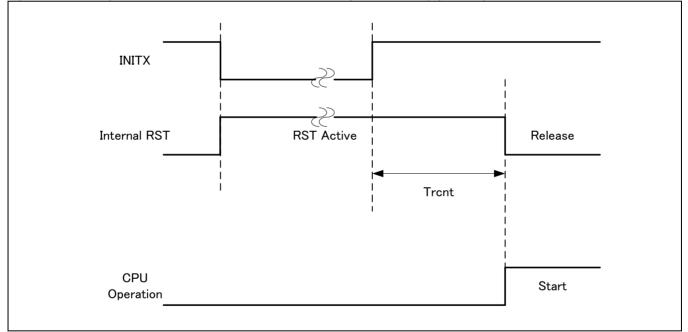
Return Count Time

 $(V_{CC} = 2.7V \text{ to } 5.5V, \text{ Ta} = -40^{\circ}\text{C to} + 105^{\circ}\text{C})$

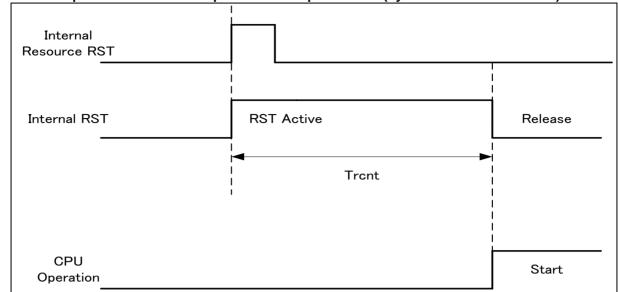
Parameter	Symbol	Value		Unit	Remarks
Falameter	Symbol	Тур	Max*	Unit	Reindiks
SLEEP mode		208	378	μs	
High-speed CR TIMER mode, Main TIMER mode, PLL TIMER mode		208	378	μs	
Low-speed CR TIMER mode	Trcnt	398	758	μs	
Sub TIMER mode		490	849	μs	
RTC/STOP mode		288	538	μs	

*: The maximum value depends on the accuracy of built-in CR.

Operation example of return from Low-Power consumption mode (by INITX)







Operation example of return from low power consumption mode (by internal resource reset*)

*: Internal resource reset is not included in return factor by the kind of Low-Power consumption mode.

Notes:

- The return factor is different in each Low-Power consumption modes.
- See "Chapter: Low Power Consumption Mode" and "Operations of Standby Modes" in FM0+ Family PERIPHERAL MANUAL.
 When interrupt recoveries, the operation mode that CPU recoveries depends on the state before the Low-Power consumption mode transition. See "CHAPTER: Low Power Consumption Mode" in "FM0+ Family PERIPHERAL MANUAL".
- The time during the power-on reset/low-voltage detection reset is excluded. See "12.4.7 Power-on Reset Timing " for the detail on the time during the power-on reset/low -voltage detection reset.
- When in recovery from reset, CPU changes to the high-speed CR run mode. When using the main clock or the PLL clock, it is necessary to add the main clock oscillation stabilization wait time or the main PLL clock stabilization wait time.
- The internal resource reset means the watchdog reset and the CSV reset.

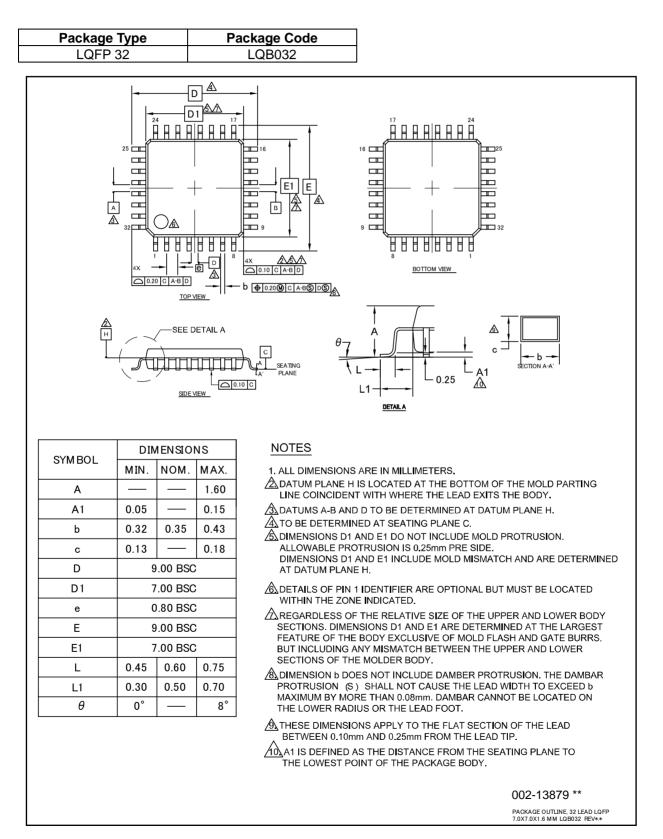


13. Ordering Information

Part number	On-chip Flash memory	On-chip SRAM	Package	Packing
S6E1A11B0AGP20000	56Kbyte	6Kbyte	Plastic • LQFP (0.80mm pitch), 32pins	Trov
S6E1A12B0AGP20000	88Kbyte	6Kbyte	(LQB032)	Tray
S6E1A11B0AGN20000	56Kbyte	6Kbyte		Trov
S6E1A12B0AGN20000	88Kbyte	6Kbyte	Plastic • QFN (0.50mm pitch), 32pins	Tray
S6E1A11B0AGN2B000	56Kbyte	6Kbyte	(WNU032)	Taping
S6E1A12B0AGN2B000	88Kbyte	6Kbyte		
S6E1A11C0AGV20000	56Kbyte	6Kbyte	Plastic • LQFP (0.50mm pitch), 48pins	Trov
S6E1A12C0AGV20000	88Kbyte	6Kbyte	(LQA048)	Tray
S6E1A11C0AGN20000	56Kbyte	6Kbyte		Trov
S6E1A12C0AGN20000	88Kbyte	6Kbyte	Plastic • QFN (0.50mm pitch), 48pins (WNY048)	Tray
S6E1A11C0AGN2B000	56Kbyte	6Kbyte		Taning
S6E1A12C0AGN2B000	88Kbyte	6Kbyte		Taping
S6E1A11C0AGF20000	56Kbyte	6Kbyte	Plastic • LQFP (0.65mm pitch), 52pins	Tray
S6E1A12C0AGF20000	88Kbyte	6Kbyte	(LQC052)	

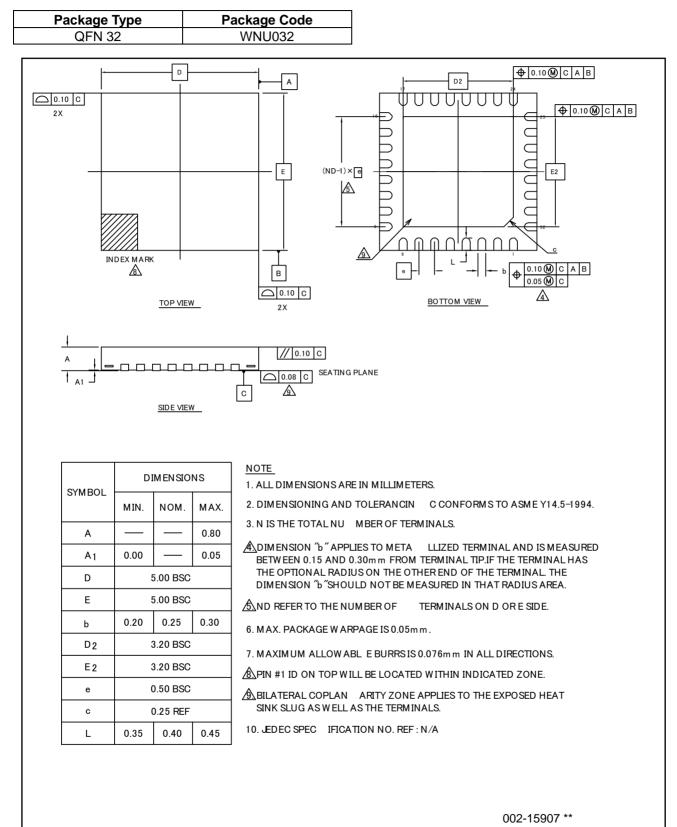


14. Package Dimensions



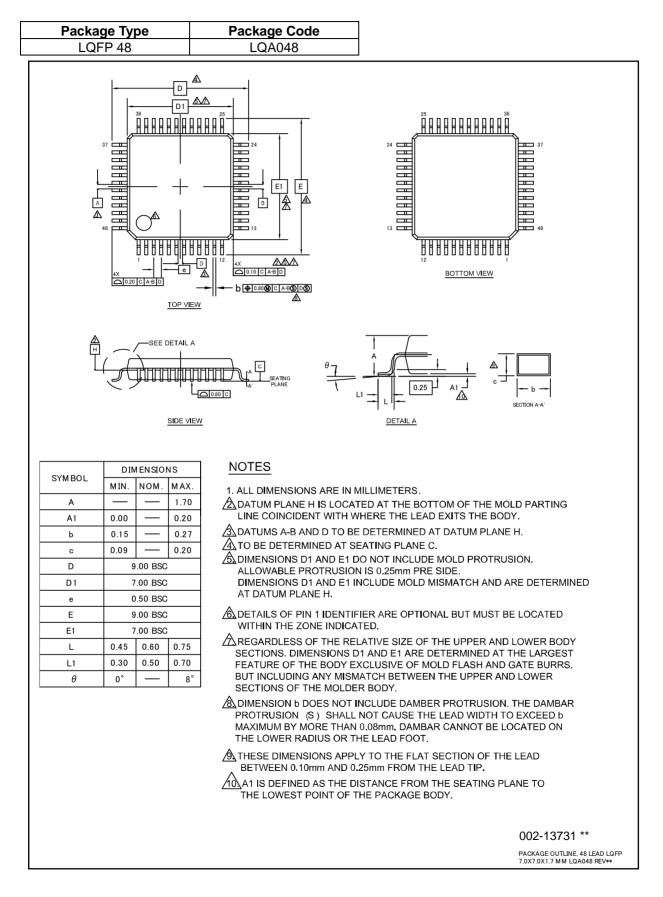






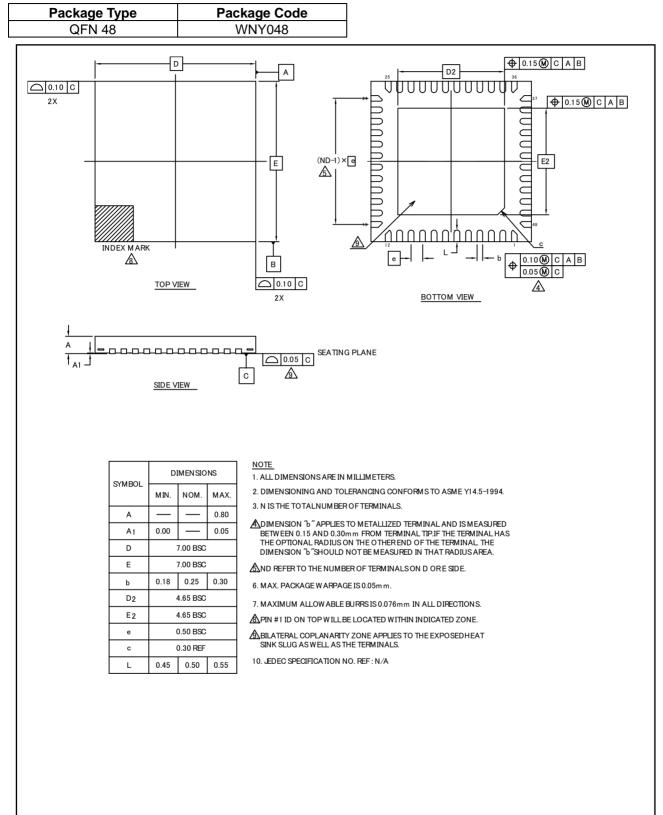
PACKAGE OUTLINE, 32 LEAD QFN 5.00X5.00X0.80 M M W N U032 3.20X8.20 M M EPAD (SAW N) REV∞





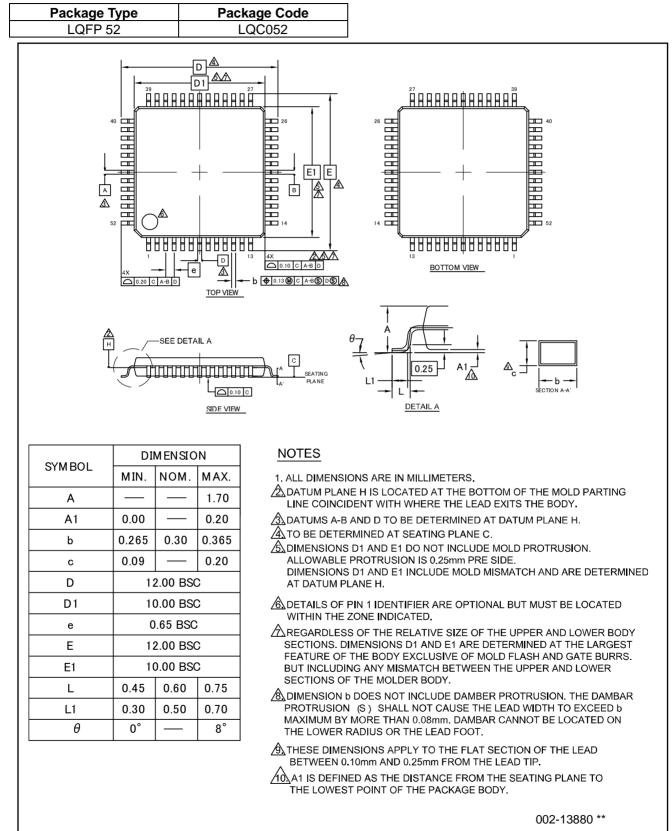






PACKAGE OUTLINE, 48 LEAD QFN 7.00X7.00X0.80 M M WNY048 4.65%4.65 M M EPAD (SAWN) REV≉







15. Major Changes

Spansion Publication Number: S6E1A1_DS710-00001

Page	Section	Change Results		
Revision ().1			
-	-	Initial release		
Revision 1	I.0 [July 16,2014]			
-	-	Revised from "Preliminary" to "Full Production"		
3	1. Description	Revised from "TYPE1" product to "TYPE1-M0+" product		
5	2. Features	Revised "Processor version"		
6	2. Features	Revised "Conversion time" of 12-bit A/D converter		
9	3. Product Lineup	Added "Note" for accuracy of built-in CR		
21,22,23 , 24,25	6. List of Pin Functions List of pin functions	Revised Pin number 30 and 31 of LQFP-32 and QFN-32		
23	6. List of Pin Functions List of pin functions	Revised Function description of SOT1_x(SDA1_x)		
40	12. Memory Map Memory map (1)	Revised from "MTB resister" to "MTB resister(SFR)"		
41	12. Memory Map Memory map (2)	Revised product name and RAM address		
46	14. Electrical Characteristics14.1 Absolute Maximum Ratings	Revised Analog pin input voltage		
47	14. Electrical Characteristics14.2 Recommended Operating Conditions	Added note "*2"		
48,49,50	14. Electrical Characteristics14.3 DC Characteristics14.3.1 Current Rating	 Revised and added "Conditions" Revised the value of "TBD" 		
52	14. Electrical Characteristics14.4 AC Characteristics14.4.1 Main Clock Input Characteristics	Revised the value of "Internal operating clock frequency" and "Internal operating clock cycle time"		
54	14. Electrical Characteristics 14.4 AC Characteristics 14.4.3 Built-in CR Oscillation Characteristics	Revised the value of "TBD"		
55	 14. Electrical Characteristics 14.4 AC Characteristics 14.4.5 Operating Conditions of Main PLL(In the case of using the built-in high-speed CR clock as the input clock of the main PLL) 	 Revised the value of "TBD" Revised the maximum value of "Main PLL clock frequency" 		
56	14. Electrical Characteristics14.4 AC Characteristics14.4.7 Power-on Reset Timing	 Revised the value of "TBD" Revised from "LVDL_minimum" to "VDH_minimum" 		
78	14. Electrical Characteristics 14.4 AC Characteristics 14.4.12 I2C Timing	 Revised the condition of "Noise filter" Revised the note for noise filter 		
80	14. Electrical Characteristics 14.5 12-bit A/D Converter	 Revised the value of "Conversion time", "Sampling time" and "Compare clock cycle" Revised the value of "State transition time to operation permission" Revised the note 		
83,84	14. Electrical Characteristics14.6 Low-voltage DetectionCharacteristics	Revised the value of SVHR and SVHI		
85	14. Electrical Characteristics 14.7 Flash Memory Write/Erase Characteristics	 Revised the value of "TBD" Revised the value of typical 		



Page	Section	Change Results	
86,88	14. Electrical Characteristics 14.8 Return Time from Low-Power Consumption Mode	Revised the value of "TBD"	
90	15. Ordering Information	Revised from "LCC-52P-M02" to "FPT-52P-M02"	

NOTE: Please see "Document History" about later revised information.



Document History

Document Title: S6E1A Series, 32-bit Arm® Cortex®-M0+ FM0+ Microcontroller

Document Number: 002-05091

Revision	ECN	Orig. of Change	Submission Date	Description of Change
**	-	AKIH	07/16/2014	Migrated to Cypress and assigned document number 002-05091. No change to document contents or format.
*A	5131394	AKIH	02/10/2016	Updated to Cypress template.
*В	5626717	HTER	04/13/2017	 Modified RTC description in "Features, Real-Time Clock(RTC)". Changed starting count value from 01 to 00. Deleted "second, or day of the week" in the Interrupt function (Page 2) Updated Package code and dimensions as follows (Page 7-12, 87-92) FPT-32P-M30 -> LQB032 FPT-48P-M49 -> LQA048 FPT-52P-M02 -> LQC052 LCC-32P-M73 -> WNU032 LCC-48P-M74 -> WNY048 Updated "12.4.7 Power-on Reset Timing". Changed parameter from "Power Supply rise time (Tr) [ms]" to "Power ramp rate (dV/dt) [mV/us]" and add some comments (Page 54) Modified the Chapter name "12.4.9 CSIO Timing" to "12.4.9 CSIO/UART Timing". (Page 56) Added the Baud rate spec in "12.4.9 CSIO Timing". (Page 56-61) Modified "12.4.9 CSIO Timing". Deleted "SPI=1, MS=0" in the titles and added MS=0,1 in the schematic (Page 63-70) Deleted the DMAC description. (Page 1, 6, 36-39, 48) Modified according to the Datasheet Errata (002-05092 Rev. **) as below. Deleted the Pin name of no available. (Page 8-9, 17, 21) Fixed typo from SCLKx_0 to SCKx_0. (Page 56-61) Added the note. (Page 63-69) Corrected the Ordering Information table. (Page 87)
*C	6062224	HUAL	02/07/2018	 Updated Figure of I/O Circuit type A and type D Modified the A/D Converter value in the table 12.5 the changed sampling time is for min value when AVcc < 4.5V for S6E1AxC0A part and this value is changed from 0.5 to 0.3.
*D	6602393	ΧΙΤΟ	06/24/2019	Updated to new template.



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